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Seven indices were prepared as a service for the subscribers to this journal. They are as follows:

INDEX	PAGES
Articles	
Author	300–314
Subject	315–319
Departments	
Computer Programs	320–321
Technical Aids	322
Books Reviewed ...	323–333
Book Reviewers ...	334–335
Corrigenda	336–339

All articles, including material that appears in the Computer Programs and Technical Aids Departments, are listed alphabetically by author and numbered sequentially. These numbers are used to cross-reference the subject index to the author index. Books reviewed are listed alphabetically by book title and have been given numbers preceded by the letter B for cross-referencing from the index of book reviewers.

ARTICLES

Vo. (Mo. Yr.) Pages

A

1. ADAMS, B. A. AND TSENG, I-T., *Robustness of Forecast-Based Monitoring Schemes* . . . . . 30 (Oct. '98) 328–339
2. ADKE, S. R. AND HONG, X., *A Supplementary Test Based on the Control Chart for Individuals* . . . . . 29 (Jan. '97) 016–020
3. AGRAWAL, R.; LAWLESS, J. F.; AND MACKAY, R. J., *Analysis of Variation Transmission in Manufacturing Processes—Part II* . . . . . 31 (Apr. '99) 143–154
4. AHN, C. W.; CHAE, K. C.; AND CLARK, G. M., *Estimating Parameters Of The Power Law Process Having Two Measures Of Failure Time* . . . . . 30 (Apr. '98) 127–132
5. ALBIN, S. L., *The Lognormal Distribution for Modeling Quality Data when the Mean is Near Zero* . . . . . 22 (Apr. '90) 105–110
6. ALBIN, S. L.; KANG, L.; AND SHEA, G., *An X and EWMA Chart for Individual Observations* . . . . . 29 (Jan. '97) 041–048
7. ALLOWAY, J. A., JR. AND RAGHAVACHARI, M., *Control Chart Based on the Hodges-Lehmann Estimator* . . . . . 23 (Oct. '91) 336–347
8. AMES, A. E.; MATTUCCI, N.; MACDONALD, S.; SZONYI, G.; AND HAWKINS, D. M., *Quality Loss Functions for Optimization Across Multiple Response Surfaces* . . . . . 29 (Jul. '97) 339–346
9. AMIN, R. W. AND ETHRIDGE, R. A., *A Note on Individual and Moving Range Control Charts* . . . . . 30 (Jan. '98) 070–074
10. AMIN, R. W. AND LEE, S. J., *The Effects of Autocorrelation and Outliers on Two-Sided Tolerance Limits* . . . . . 31 (Jul. '99) 286–300
11. AMIN, R. W. AND MILLER, R. W., *A Robustness Study of $\bar{X}$ Charts with Variable Sampling Intervals* . . . . . 25 (Jan. '93) 036–044
12. AMIN, R. W.; WOLFF, H.; BESENFELDER, W.; AND BAXLEY, R., JR., *EWMA Control Charts for the Smallest and Largest Observations* . . . . . 31 (Apr. '99) 189–206
13. ANDERE-RENDON, J.; MONTGOMERY, D. C.; AND ROLLIER, D. A., *Design of Mixture Experiments Using Bayesian D-Optimality* . . . . . 29 (Oct. '97) 451–463
14. ANDERSON-COOK, C. M., *A Tutorial on One-Way Analysis of Circular-Linear Data* . . . . . 31 (Jan. '99) 109–119
15. ANKENMAN, B. E., *Design of Experiments with Two- and Four-Level Factors* 31 (Oct. '99) 363–375
16. ARCELUS, F. J. AND RAHIM, M. A., *Simultaneous Economic Selection of a Variables and an Attribute Target Mean* . . . . . 26 (Apr. '94) 125–133
17. ATIENZA, O. O.; TANG, L. C.; AND ANG, B. W., *A SPC Procedure for Detecting Level Shifts of Autocorrelated Processes* . . . . . 30 (Oct. '98) 340–351
18. ATWOOD, C. L. AND ENGELHARDT, M., *Techniques for Uncertainty Analysis of Complex Processes* . . . . . 28 (Jan. '96) 001–011

B

19. BAI, D. S. AND CHOI, I. S., *$\bar{X}$ and R Control Charts for Skewed Populations* 27 (Apr. '95) 120–131
20. BAIN, L. J. AND ENGELHARDT, M., *Reliability Test Plans for One-Shot Devices Based on Repeated Samples* . . . . . 23 (Oct. '91) 304–311
21. BAIN, P. T. AND PATEL, J. K., *Factors for Calculating Prediction Intervals for Samples from a One-Parameter Exponential Distribution* . . . . . 23 (Jan. '91) 048–052
22. BANKS, D. L. AND PARMIGIANI, G., *Pre-Analysis of Superlarge Industrial Data Sets* . . . . . 24 (Jul. '92) 115–129
23. BARTON, R. R., *Design-Plots for Factorial and Fractional Factorial Designs* . . 30 (Jan. '98) 040–054

24. BARTON, R. R., *Pre-Experiment Planning for Designed Experiments: Graphical Methods* . . . 29 (Jul. '97) 307–316
25. BAXLEY, R. V.,JR., *An Application of Variable Sampling Interval Control Charts* 27 (Oct. '95) 275–282
26. BEBBINGTON, M. S. AND GOVINDARAJU, K., *On Pesotchinsky's Scheme for Very Low Fraction Nonconforming* . . . 30 (Jul. '98) 248–253
27. BENSKI, H. C., *Use of a Normality Test to Identify Significant Efects in Factorial Designs* . . . 21 (Jul. '89) 174–178
28. BERK, K. N. AND PICARD, R. R., *Significance Tests for Saturated Orthogonal Arrays* . . . 23 (Apr. '91) 079–089
29. BINGHAM, T. C., *An Approach to Developing Multi-Level Fractional Factorial Designs* . . . 29 (Oct. '97) 370–380
30. BISGAARD, S., *Blocking Generators for Small 2^{k-p} Designs* . . . 26 (Oct. '94) 288–296
31. BISGAARD, S., *A Method for Identifying Defining Contrasts Contrasts for 2^{k-p} Experiments* . . . 25 (Jan. '93) 028–035
32. BISGAARD, S. AND FULLER, H. T., *Sample Size Estimates for 2^{k-p} Designs with Binary Responses* . . . 27 (Oct. '95) 344–354
33. BLACK, S. E. AND RIGDON, S. E., *Statistical Inference for a Modulated Power Law Process* . . . 28 (Jan. '96) 081–090
34. BLACKWOOD, L. G. AND BRADLEY, E. L., *An Omnibus Test for Comparing Two Measuring Devices* . . . 23 (Jan. '91) 012–016
35. BODDEN, K. M. AND RIGDON, S. E., *A Program for Approximating the In-Control ARL for the MEWMA Chart* . . . 31 (Jan. '99) 120–123
36. BORROR, C. M.; CHAMP, C. W.; AND RIGDON, S. E., *Poisson EWMA Control Charts* . . . 30 (Oct. '98) 352–361
37. BORROR, C. M.; MONTGOMERY, D. C.; AND RUNGER, G. C., *Robustness of the EWMA Control Chart to Non-normality* . . . 31 (Jul. '99) 309–316
38. BOUCHER, T. O. AND JAFARI, M. A., *The Optimum Target Value for Single Filling Operations with Quality Sampling Plans* . . . 23 (Jan. '91) 044–047
39. BOURKE, P. D., *Detecting a Shift in Fraction Nonconforming Using Run Length Control Charts with 100% Inspection* . . . 23 (Jul. '91) 225–238
40. BOX, G. E. P., *Response* . . . 31 (Jan. '99) 067–072
41. BOX, G. E. P., *Statistics as a Catalyst to Learning by Scientific Method, Part II —A Discussion* . . . 31 (Jan. '99) 016–029
42. BOX, G. E. P.; COLEMAN, D. E.; AND BAXLEY, R. V., JR., *A Comparison of Statistical Process Control and Engineering Process Control* . . . 29 (Apr. '97) 128–130
43. BOX, G. E. P. AND LIU, P. Y. T., *Statistics as a Catalyst to Learning by ScientificMethod, Part I—An Example* . . . 31 (Jan. '99) 001–015
44. BOX, G. AND LUCEÑO, A., *Discrete Proportional-Integral Adjustment and Statistical Process Control* . . . 29 (Jul. '97) 248–260
45. BOX, G. E. P. AND MEYER, R. D., *Finding the Active Factors in Fractionated Screening Experiments* . . . 25 (Apr. '93) 094–105
46. BOYLES, R. A., *Estimating Common-Cause Sigma in the Presence of Special Causes* . . . 29 (Oct. '97) 381–395
47. BOYLES, R. A., *Exploratory Capability Analysis* . . . 28 (Jan. '96) 091–098
48. BOYLES, R. A., *The Taguchi Capability Index* . . . 23 (Jan. '91) 017–026
49. BRUGGER,R.M., *A Simplified Markov Chain Analysis of ANSl/ASQC Z1.4 Used Without Limit Numbers* . . . 21 (Apr. '89) 097–102
50. BULLINGTON, K. E.; HOOL, J. N.; AND MAGHSOODLOO, S., *A Simple Method for Obtaining Resolution IV Designs for Use with Taguchi's Orthogonal Arrays* 22 (Oct. '90) 260–264
51. BULLINGTON, R.G.; LOVIN, S.; MILLER, D.M.; AND WOODALL, W. H., *Improvement of an Industrial Thermostat Using Designed Experiments* . . . 25 (Oct. '93) 262–270
52. BURDICK, R. K., *Using Confidence Intervals to Test Variance Components* . . . 26 (Jan. '94) 030–038

53. BURDICK, R. K. AND LARSEN, G. A., *Confidence Intervals on Measures of Variability in R&R Studies* . . . . . 29 (Jul. '97) 261–273

C

54. CAIN, M. AND JANSSEN, C., *Target Selection in Process Control Under Asymmetric Costs* . . . . . 29 (Oct. '97) 464–468
55. CHAKRABORTI, S. AND GIBBONS, J. D., *One-Sided Nonparametric Comparison of Treatments with a Standard in the One-Way Layout* . . . . . 23 (Apr. '91) 102–106
56. CHAMP, C. W. AND RIGDON, S. E., *An Analysis of the Run Sum Control Chart* 29 (Oct. '97) 407–417
57. CHAMP, C. W. AND WOODALL, W. H., *A Program to Evaluate the Run Length Distribution of a Shewhart Control Chart with Supplementary Runs Rules* . . 22 (Jan. '90) 068–073
58. CHANG, J. T. AND FRICKER, R. D., JR., *Detecting When a Monotonically Increasing Mean Has Crossed a Threshold* . . . . . 31 (Apr. '99) 217–234
59. CHANG, T. C. AND GAN, F. F., *A Cumulative Sum Control Chart for Monitoring Process Variance* . . . . . 27 (Apr. '95) 109–119
60. CHEN, G., *An Improved p Chart Through Simple Adjustments* . . . . . 30 (Apr. '98) 142–151
61. CHEN, G. AND BALAKRISHNAN, N., *A General Purpose Approximate Goodness-of-Fit Test* . . . . . 27 (Apr. '95) 154–161
62. CHEN, W., *The Effects of SPC on the Target of Process Quality Improvement* . 28 (Apr. '96) 224–232
63. CHIPMAN, H., *Handling Uncertainty in Analysis of Robust Design Experiments* 30 (Jan. '98) 011–017
64. CHOU, Y.-M.; OWEN, D. B.; AND BORREGO A., S. A., *Lower Confidence Limits on Process Capability Indices* . . . . . 22 (Jul. '90) 223–229
65. CHOU, Y-M; POLANSKY, A. M.; AND MASON, R. L., *Transforming Non-Normal Data To Normality In Statistical Process Control* . . . . . 30 (Apr. '98) 133–141
66. CHUN, Y. H. AND RINKS, D. B., *Three Types of Producer's and Consumer's Risks in the Single Sampling Plan* . . . . . 30 (Jul. '98) 254–268
67. CIMINERA, J. L.; HEYSE, J. F.; AND TUKEY, J. W., *Techniques for the Graphical Analysis of Possibly Skewed Measurements* . . . . . 21 (Oct. '89) 223–231
68. CIMINERA, J. L. AND TUKEY, J. W., *Control-Charting Automated Laboratory Instruments when many Successive Differences may be Zero* . . . . . 21 (Jan. '89) 007–015
69. CIMINERA, J. L. AND TUKEY, J. W., *Use of Augmented Box Plots for Reviewing Measurement Results Collected Over Time* . . . . . 21 (Jul. '89) 187–198
70. COLLANI, E. V. AND SHELL, J., *An Approach to Controlling Process Variability* 21 (Apr '89) 087–096
71. COPELAND, K. A. F. AND NELSON, P. R., *Dual Response Optimization via Direct Function Minimization* . . . . . 28 (Jul. '96) 331–336
72. CORNELL, J. A., *Embedding Mixture Experiments Inside Factorial Experiments* 22 (Oct. '90) 265–276
73. CORNELL, J. A., *Fitting Models to Data from Mixture Experiments Containing Other Factors* . . . . . 27 (Jan. '95) 013–033
74. CORNELL, J. A. AND MONTGOMERY, D. C., *Interaction Models as Alternatives to Low-Order Polynomials* . . . . . 28 (Apr. '96) 163–176
75. COSTA, A. F. B., *AATS for the $\bar{X}$ Chart with Variable Parameters* . . . . . 31 (Oct. '99) 455–458
76. COSTA, A. F. B., *Joint $\bar{X}$ and R Charts with Variable Sample Sizes and Sampling Intervals* . . . . . 31 (Oct. '99) 387–397
77. COSTA, A. F. B., *$\bar{X}$ Chart with Variable Sample Size and Sampling Intervals* . 29 (Apr. '97) 197–204
78. COSTA, A. F. B., *$\bar{X}$ Charts with Variable Parameters* . . . . . 31 (Oct. '99) 408–416
79. COSTA, A. F. B., *$\bar{X}$ Charts with Variable Sample Size* . . . . . 26 (Jul. '94) 155–163
80. CROSIER, R. B., *FORTRAN Programming Techniques* . . . . . 23 (Oct. '91) 348–354
81. CROSIER, R. B., *Symmetric Orientations for Simplex Designs* . . . . . 28 (Apr. '96) 148–152
82. CROWDER, S. V., *Design of Exponentially Weighted Moving Average Schemes* 21 (Jul. '89) 155–162
83. CROWDER, S. V. AND HAMILTON, M., *An EWMA for Monitoring a Process Standard Deviation* . . . . . 24 (Jan. '92) 012–021

84. CRYER, J. D. AND RYAN, T. P., *The Estimation of Sigma for an X Chart: MR/d_2 or S/c_4?* . . . . . 22 (Jul. '90) 187–192

D

85. DAUDIN, J. J., *Double Sampling $\bar{X}$ Charts* . . . . . 24 (Apr. '92) 078–087
86. DAVIS, R. B., *Designing S-Charts with Two Average Run Length Constraints* 31 (Apr. '99) 246–248
87. DEL CASTILLO, E., *Discussion* . . . . . 27 (Oct. '95) 316–321
88. DEL CASTILLO, E., *Evaluation of Run Length Distribution for $\bar{X}$ Charts with Unknown Variance* . . . . . 28 (Jan. '96) 116–122
89. DEL CASTILLO, E., *Multiresponse Process Optimization via Constrained Confidence Regions* . . . . . 28 (Jan. '96) 061–070
90. DEL CASTILLO, E.; FAN,S.-K.; AND SEMPLE, J., *The Computation of Global Optima in Dual Response Systems* . . . . . 29 (Jul. '97) 347–353
91. DEL CASTILLO, E. AND HURWITZ, A. M., *Run-to-Run Process Control: Literature Review and Extensions* . . . . . 29 (Apr. '97) 184–196
92. DEL CASTILLO, E. AND MONTGOMERY, D. C., *A Nonlinear Programming Solution to the Dual Response Problem* . . . . . 25 (Jul. '93) 199–204
93. DEL CASTILLO, E.; MONTGOMERY, D. C.; AND MCCARVILLE, D. R., *Modified Desirability Functions for Multiple Response Optimization* . . . . . 28 (Jul. '96) 337–345
94. DEUTLER, T., *Grubbs-Type Estimators for Reproducibility Variances in an Interlaboratory Test Study* . . . . . 23 (Oct. '91) 324–335
95. DHAVALE, D. G., *Computational Approaches to Estimating Negative Binomial Parameters from Count Data* . . . . . 21 (Jan. '89) 051–064
96. DOGANAKSOY, N. AND HAHN, G. J., *Discussion* . . . . . 31 (Jan. '99) 047–053
97. DOGANAKSOY, N. AND HAHN, G. J., *Evaluating the Potential Impact of Blending on Product Consistency* . . . . . 28 (Jan. '96) 051–060
98. DOGANAKSOY, N. AND HAHN, G. J., *Moving From Every-Lot Inspection to Audit Sampling* . . . . . 26 (Oct. '94) 261–273
99. DOGANAKSOY, N.; SCHMEE, J.; AND VANDEVEN, M., *Process Monitoring with Multiple Product Grades* . . . . . 28 (Jul. '96) 346–355
100. DOLEZAL, K. K.; BURDICK, R. K.; AND BIRCH, N. J., *Analysis Of A Two-Factor R & R Study With Fixed Operators* . . . . . 30 (Apr. '98) 163–170
101. DOWNS, B. T. AND GROUT, J. R., *An Economic Analysis of Inspection Costs for Mistake-Proofing Binomial Attributes* . . . . . 31 (Oct. '99) 417–426
102. DRAPER, N. R. AND GUTTMAN, I., *Two-Level Factorial and Fractional Factorial Designs in Blocks of Size Two* . . . . . 29 (Jan. '97) 071–075

E

103. EASTERLING, R. G.; JOHNSON, M. E.; BEMENT, T. R.; AND NACHTSHEIM, C. J., *Statistical Tolerancing Based on Consumer's Risk Considerations* . . . . . 23 (Jan. '91) 001–011
104. EBERHARDT, K. R. AND MEE, R. W., *Constant-Width Calibration Intervals for Linear Regression* . . . . . 26 (Jan. '94) 021–029
105. EBIBL, S.; KESS U.; AND PUKELSHEIM, F., *Quality Planning of Manufacturing Processes: Achieving a Target Value* . . . . . 24 (Jan. '92) 022–026
106. EBRAHIMI, N. AND DUNNIGAN, K., *Two Programs for System Reliability Computation* . . . . . 30 (Jan. '98) 093–099
107. ENGEL, J. AND DE VRIES, B., *Evaluating a Well-Known Criterion for Measurement Precision* . . . . . 29 (Oct. '97) 469–476

F

108. FALTIN, F. W.; MASTRANGELO, C. M.; RUNGER, G. C.; AND RYAN, T. P., *Considerations in Monitoring of Autocorrelated and Independent Data* . . . . . 29 (Apr. '97) 131–133
109. FALTIN, F. W. AND WOODALL, W. H., *Discussion* . . . . . 23 (Jul. '91) 194–197
110. FANG, J. AND CASE, K. E., *Using a Correlation Test for Normality* . . . . . 28 (Jul. '96) 356–362
111. FARNUM, N. R., *Control Charts for Short Runs: Nonconstant Process and Measurement* . . . . . 24 (Jul. '92) 138–144
112. FARNUM, N. R., *Discussion* . . . . . 27 (Oct. '95) 322–323
113. FATHI, Y., *Producer-Consumer Tolerances* . . . . . 22 (Apr. '90) 138–145
114. FOUNTAIN, R. L. AND CHOU, Y.-M., *Minimum Sample Sizes for Two-Sided Tolerance Intervals for Finite Populations* . . . . . 23 (Apr. '91) 090–095
115. FRANKLIN, L. A. AND WASSERMAN, G. S., *Bootstrap Lower Confidence Limits for Capability Indices* . . . . . 24 (Oct. '92) 196–210
116. FRIEDRICHS, M. D. AND GUENTHER, W. C., *Normal and Binomial Selection Problems* . . . . . 21 (Jan. '89) 041–045

G

117. GAN, F. F., *Computing the Percentage Points of the Run Length Distribution of an Exponentially Weighted Moving Average Control Chart* . . . . . 23 (Oct. '91) 359–365
118. GAN, F. F., *Design of Optimal Exponential CUSUM Control Charts* . . . . . 26 (Apr. '94) 109–124
119. GAN, F. F., *Designs of One- and Two-Sided Exponential EWMA Charts* . . . . 30 (Jan. '98) 055–069
120. GAN, F. F., *An Optimal Design of CUSUM Quality Control Charts* . . . . . 23 (Oct. '91) 279–286
121. GAN, F. F., *The Run Length Distribution of a Cumulative Sum Control Chart* 25 (Jul. '93) 205–215
122. GAN, F. F. AND CHOI, K. P., *Computing Average Run Lengths for Exponential CUSUM Schemes* . . . . . 26 (Apr. '94) 134–143
123. GAN, F. F. AND KOEHLER, K. J., *A Goodness-of-Fit Test Based on P – P Probability Plots* . . . . . 24 (Apr. '92) 096–102
124. GIBBONS, D. I. AND MCDONALD, G. C., *Constrained Regression Estimates of Technology Effects on Fuel Economy* . . . . . 31 (Apr. '99) 235–245
125. GLEN, A. G. AND LEEMIS, L. M., *The Arctangent Survival Distribution* . . . . 29 (Apr. '97) 205–210
126. GOVINDARAJU, K., *Procedures and Tables tbr the Selection of CSP-I Plans* . . . 21 (Jan. '89) 046–050
127. GOVINDARAJU, K., *Single Sampling Plans for Variables Indexed by AQL and AOQL* . . . . . 22 (Oct. '90) 310–313
128. GRABOV, P. AND INGMAN, D., *Adaptive Control Limits for Bivariate Process Monitoring* . . . . . 28 (Jul. '96) 320–330
129. GREGO, J. M., *Generalized Linear Models and Process Variation* . . . . . 25 (Oct. '93) 288–295
130. GRIMSHAW, S. D. AND ALT, F. B., *Control Charts for Quantile Function Values* 29 (Jan. '97) 001–007
131. GRIZE, Y. L., *Plotting Scaled Effects from Unreplicated Orthogonal Experiments* 23 (Jul. '91) 205–212
132. GUIRGUIS, G. H. AND RODRIGUEZ, R.N., *Computation of Owen's Q Function Applied to Process Capability Analysis* . . . . . 24 (Oct. '92) 236–246

H

133. HACKL, P. AND LEDOLTER, J., *A Control Chart Based on Ranks* . . . . . 23 (Apr. '91) 117–124
134. HALLINAN, A. J. JR., *A Review of the Weibull Distribution* . . . . . 25 (Apr. '93) 085–093
135. HAMADA, M., *An Explanation and Criticism of Minute Accumulating Analysis* 24 (Apr. '92) 070–077
136. HAMADA, M; MACKAY, R. J.; AND WHITNEY, J. B., *Continuous Process Improvement with Observational Studies* . . . . . 25 (Apr. '93) 077–084
137. HAMADA, M. AND NELDER, J. A., *Generalized Linear Models for Quality-Improvement Experiments* . . . . . 29 (Jul. '97) 292–304

138. HAMADA, M. AND TSE, S. K., *The Existence of Maximum Likelihood Estimates from Designed Experiments* . . . . . 28 (Apr. '96) 244–254
139. HAMADA, M. AND WU, C. F. J., *Analysis of Designed Experiments with Complex Aliasing* . . . . . 24 (Jul. '92) 130–137
140. HAMADA, M. AND WU, C. F. J., *The Treatment of Related Experimental Factors by Sliding Levels* . . . . . 27 (Jan. '95) 045–055
141. HAMILTON, M.D., *Average Run Lengths of Exponentially Weighted Moving Average Control Charts for Monitoring a Process Standard Deviation* . . . . . 24 (Jan. '92) 044–050
142. HAWKINS, D. M., *Discussion* . . . . . 27 (Oct. '95) 324–327
143. HAWKINS, D. M., *A Fast Accurate Approximation for In-control and Out-of -Control Average Run Lengths for CUSUMS* . . . . . 24 (Jan. '92) 037–043
144. HAWKINS, D. M., *Regression Adjustment for Variables in Multivariate Quality Control* . . . . . 25 (Jul. '93) 170–182
145. HAWKINS, D. M., *Robustification of Cumulative Sum Charts by Winsorization* 25 (Oct. '93) 248–261
146. HAYTER, A. J. AND TSUI, K.-L., *Identification and Quantification in Multivariate Quality Control Problems* . . . . . 26 (Jul. '94) 197–208
147. HEIMANN, P. A., *Attributes Control Charts with Large Sample Sizes* . . . . . 28 (Oct. '96) 451–459
148. HEYES, G. B., *A Computer Program for Comparison of Multiple Poisson Means* 22 (Jul. '90) 239–244
149. HINCKLEY, C. M. AND BARKAN, P., *The Role of Variation, Mistakes, and Complexity in Producing Nonconformities* . . . . . 27 (Jul. '95) 242–249
150. HO, C. AND CASE, K. E., *Economic Design of Control Charts: A Literature Review for 1981-1991* . . . . . 26 (Jan. '94) 039–053
151. HONG, S. H. AND ELSAYED, E. A., *The Optimum Mean for Processes with Normally Distributed Measurement Error* . . . . . 31 (Jul. '99) 338–344
152. HU, S. J. AND ROAN, C., *Change Patterns of Time Series-Based Control Charts* 28 (Jul. '96) 302–312
153. HUBELE, N. F.; BEAUMARIAGE, T.; BAWEJA, G.; HONG, S.-C.; AND CHU, R., *Using Experimental Design to Assess the Capability of a System* . . 26 (Jan. '94) 001–011
154. HUNTER, J. S., *Discussion* . . . . . 31 (Jan. '99) 054–057

I

155. INGOLFSSON, A. AND SACHS, E., *Stability and Sensitivity of an EWMA Controller* . . . . . 25 (Oct. '93) 271–287
156. INMAN, J.; LEDOLTER, J.; LENTH, R.V.; AND NIEMI, L., *Two Case Studies Involving an Optical Emission Spectrometer* . . . . . 24 (Jan. '92) 027–036
157. IYER, H. K., AND VECCHIA, D. F, *Minimum Cost Inspection Intervals for a Two-State Process* . . . . . 22 (Jul. '90) 210–222

J

158. JANAKIRAM, M. AND KEATS, J. B., *Combining SPC and EPC in a Hybrid Industry* . . . . . 30 (Jul. '98) 189–200
159. JARAIEDI, M. AND ZHUANG, Z., *Determination of Optimal Design Parameters of $\bar{X}$ Charts When there is a Multiplicity of Assignable Causes* . . . . . 23 (Jul. '91) 253–258
160. JESKE, D. R. AND MARLOW, N. A., *Alternative Prediction Intervals for Pareto Proportions* . . . . . 29 (Jul. '97) 317–326
161. JIN, C. AND DAMS, R. B., *Calculation of Average Run Lengths for Zone Control Charts with Specified Zone Scores* . . . . . 23 (Oct. '91) 355–358
162. JOHNSON, N. L.; KOTZ, S.; AND RODRIGUEZ, R. N., *Statistical Effects of Imperfect Inspection Sampling IV. Modified Dorfman Screening Procedures* . 22 (Apr. '90) 128–137
163. JOHNSON, T., *The Relationship of C_{PM} to Squared Error Loss* . . . . . 24 (Oct. '92) 211–215
164. JONES, L. A. AND WOODALL, W. H., *The Performance of Bootstrap Control Charts* . . . . . 30 (Oct. '98) 362–375

165. JONES, L. A.; WOODALL, W. H.; AND CONERLY, M. D., *Exact Properties of Demerit Control Charts* . . . . . 31 (Apr. '99) 207–216

K

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167. KACKER, R. N., AND TSUI, K.-L, *Interaction Graphs: Graphical Aids for Planning Experiments* . . . . . 22 (Jan. '90) 001–014
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169. KAMINSKY, F. C.; BENNEYAN, J. C.; AND DAVIS, R. D., *Statistical Control Charts Based on a Geometric Distribution* . . . . . 24 (Apr. '92) 063–069
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175. KENETT, R. S., *Two Methods for Comparing Pareto Charts* . . . . . 23 (Jan. '91) 027–031
176. KHATTREE, R., *Robust Parameter Design: A Response Surface Approach* . . . . 28 (Apr. '96) 187–198
177. KHURI, A. I., *Discussion* . . . . . 31 (Jan. '99) 058–060
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179. KIM, K-J. AND LIN, D. K. J., *Dual Response Optimization: A Fuzzy Modeling Approach* . . . . . 30 (Jan. '98) 001–010
180. KITTLITZ, R. G., JR., *Transforming the Exponential for SPC Applications* . . . 31 (Jul. '99) 301–308
181. KOONS, G. F., *Effect of Sinter Composition on Emissions: A Multi-Component, Highly-Constrained Mixture Experiment* . . . . . 21 (Oct. '89) 261–267
182. KOONS, G. F. AND LUNER, J.J., *SPC in Low-Volume Manufacturing: A Case Study* . . . . . 23 (Oct. '91) 287–295
183. KOURTI, T. AND MACGREGOR, J. F., *Multivariate SPC Methods for Process and Product Monitoring* . . . . . 28 (Oct. '96) 409–428
184. KRISHNAMOORTHY, K. AND SHAH, A. K., *Testing Equality of Several Normal Means to a Specified Standard* . . . . . 27 (Apr. '95) 132–138
185. KUSHLER, R. H. AND HURLEY, P., *Confidence Bounds for Capability Indices* . 24 (Oct. '92) 188–195

L

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187. LEDOLTER, J. AND SWERSEY, A., *Dorian Shainin's Variables Search Procedure: A Critical Assessment* . . . . . 29 (Jul. '97) 237–247
188. LEDOLTER, J. AND SWERSEY, A., *An Evaluation of Pre-control* . . . . . 29 (Apr. '97) 163–171
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190. LIN, D. K. J., *Discussion* . . . . . 31 (Jan. '99) 061–066
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192. LIN, W. S. W. AND ADAMS, B. M., *Combined Control Charts for Forecast-Based Monitoring Schemes* . . . . . 28 (Jul. '96) 289–301

193. LOUGHIN, T. M., *Calibration Of The Lenth Test For Unreplicated Factorial Designs* . . . . . 30 (Apr. '98) 171–175
194. LU, C.-W. AND REYNOLDS, M. R., JR., *Control Charts for Monitoring the Mean and Variance of Autocorrelated Processes* . . . . . 31 (Jul. '99) 259–274
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196. LUCAS, J. M., *Control Schemes for Low Count Levels* . . . . . 21 (Jul. '89) 199–201
197. LUCAS, J. M., *How to Achieve a Robust Process Using Response Surface Methodology* . . . . . 26 (Oct. '94) 248–260
198. LUCEÑO, A., *Choosing the EWMA Parameter in Engineering Process Control* . 27 (Apr. '95) 162–168
199. LUNANI, M.; NAIR, V. N.; AND WASSERMAN, G. S., *Graphical Methods for Robust Design with Dynamic Characteristics* . . . . . 29 (Jul. '97) 327–338
200. LYNCH, R. O., *Minimum Detectable Effects for 2^{k-p} Experimental Plans* 25 (Jan. '93) 012–017

M

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202. MACGREGOR, J. F., *Discussion* . . . . . 23 (Jul. '91) 198–199
203. MACGREGOR, J. F. AND HARRIS, T. J., *The Exponentially Weighted Moving Variance* . . . . . 25 (Apr. '93) 106–118
204. MAGHSOODLOO, S., *The Exact Relation of Taguchi's Signal-to-Noise Ratio to His Quality Loss Function* . . . . . 22 (Jan. '90) 057–067
205. MANDEL, J., *The Nature of Collinearity* . . . . . 21 (Oct. '89) 268–276
206. MANDEL, J., *Some Thoughts on Variable-Selection in Multiple Regression* . . . . 21 (Jan. '89) 002–006
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216. MCCOOL, J. I. AND JOYNER-MOTLEY, T., *Control Charts Applicable When the Fraction Nonconforming is Small* . . . . . 30 (Jul. '98) 240–247
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218. MCSHANE, L. M. AND TURNBULL, B. W., *New Performance Measures for Continuous Sampling Plans Applied to Finite Production Runs* . . . . . 24 (Jul. '92) 153–161
219. MCWILLIAMS, T. P., *Acceptance Sampling Plans Based on the Hypergeometric Distribution* . . . . . 22 (Oct. '90) 319–327
220. MCWILLIAMS, T. P., *Economic Control Chart Designs and the In-Control Time Distribution: A Sensitivity Study* . . . . . 21 (Apr. '89) 103–110
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222. McWilliams, T. P., *Operating Characteristic and Average Sample Number Functions for Attribute Based Sequential Test Plans* . . . . . 21 (Apr. '89) 128–135
223. Melloy, B. J., *Determining the Optimal Process Mean and Screening Limits for Packages Subject to Compliance Testing* . . . . . 23 (Oct. '91) 318–323
224. Montgomery, D. C., *Discussion* . . . . . 31 (Jan. '99) 045–046
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232. Mortell, R. R. and Runger, G. C., *Statistical Process Control of Multiple Stream Processes* . . . . . 27 (Jan. '95) 001–012
233. Mullenix, P., *Accurate Estimation of Count Totals Using Ratio Estimators* 22 (Oct. '90) 277–282
234. Myers, R. H., *Response* . . . . . 31 (Jan. '99) 073–074
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N

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240. Naik, D. N. and Khattree, R., *A Computer Program to Estimate Variance Components in Staggered Nested Designs* . . . . . 30 (Jul. '98) 292–297
241. Nelson, L. S., *Additional Critical Values for Multiple Comparisons by Cluster Analysis* . . . . . 23 (Oct. '91) 366–368
242. Nelson, L. S., *The Anderson-Darling Test for Normality* . . . . . 30 (Jul. '98) 298–299
243. Nelson, L. S., *Answers to a True-False Test in Quality Control and Statistics* 28 (Oct. '96) 480–482
244. Nelson, L. S., *The Calculation of Process Capability Indices* . . . . . 31 (Apr. '99) 249–250
245. Nelson, L. S., *Comments on Significance Tests and Confidence Intervals* . . . . 22 (Oct. '90) 328–330
246. Nelson, L. S., *Construction and Evaluation of Closed Sequential Sign Tests* 25 (Apr. '93) 131–139
247. Nelson, L. S., *Contriving an Unavailable Significance Level* . . . . . 31 (Jul. '99) 351–352
248. Nelson, L. S., *A Control Chart for Parts-Per-Million Nonconforming Items* . 26 (Jul. '94) 239–240
249. Nelson, L. S., *Critical Values for a Cluster Analysis Approach to Multiple Comparisons* . . . . . 22 (Jan. '90) 074–077
250. Nelson, L. S., *Designing Closed Sequential Binomial Tests* . . . . . 25 (Jul. '93) 216–220
251. Nelson, L. S., *Did a Sample Come from a Specified Normal Distribution?* . . . 26 (Apr. '94) 144–145
252. Nelson, L. S., *Economic Balance of Sampling and Testing* . . . . . 24 (Jul. '92) 162–164

253. NELSON, L. S., *Evaluating Overlapping Confidence Intervals* . . . . . 21 (Apr. '89) 140–141
254. NELSON, L. S., *Factors for Confidence Limits on Standard Deviations* . . . . . 29 (Oct. '97) 485–487
255. NELSON, L. S., *Graphical Tests for Association* . . . . . 29 (Jan. '97) 111–112
256. NELSON, L. S., *Interpolation for Intermediate Significance Levels* . . . . . 28 (Apr. '96) 255–256
257. NELSON, L. S., *The Mean Square Successive Difference Test Automated* . . . . . 30 (Oct. '98) 401–402
258. NELSON, L. S., *Monitoring Reduction in Variation with a Range Chart* . . . . . 22 (Apr. '90) 163–165
259. NELSON, L. S., *Notes on the Shewhart Control Chart* . . . . . 31 (Jan. '99) 124–126
260. NELSON, L. S., *Notes on the Use of Randomization in Experimentation* . . . . . 28 (Jan. '96) 123–126
261. NELSON, L. S., *Polynomial Interpolation* . . . . . 23 (Jul. '91) 259–262
262. NELSON, L. S., *Power in Comparing Poisson Means: I. One-Sample Test* . . . . 23 (Jan. '91) 068–070
263. NELSON, L. S., *Power in Comparing Poisson Means: II. Two-Sample Test* . . . 23 (Apr. '91) 163–166
264. NELSON, L. S., *A Program for Tables of the Binomial and Hypergeometric Distributions* . . . . . 26 (Oct. '94) 318–321
265. NELSON, L. S., *Propagation of Error* . . . . . 24 (Oct. '92) 232–235
266. NELSON, L. S., *Randomization Test for Linear Correlation/Regression* . . . . . 29 (Jul. '97) 354–356
267. NELSON, L. S., *A Randomization Test for Ordered Alternatives* . . . . . 24 (Jan. '92) 051–053
268. NELSON, L. S., *The Rank Sum Test with Confidence Limits* . . . . . 25 (Oct. '93) 306–310
269. NELSON, L. S., *Sample Sizes for Confidence Intervals with Specified Lengths and Tolerances* . . . . . 26 (Jan. '94) 054–063
270. NELSON, L. S., *Sample Sizes for Two-Sample Tests on Means* . . . . . 24 (Apr. '92) 103–108
271. NELSON, L. S., *Setting Up a Control Chart Using Subgroups of Varying Sizes* . 22 (Jul. '90) 245–246
272. NELSON, L. S., *Single Test that Two Samples Came from the Same Normal Distribution* . . . . . 27 (Jan. '95) 084–087
273. NELSON, L. S., *Shewhart Control Charts with Unequal Subgroup Sizes* . . . . . 26 (Jan. '94) 064–067
274. NELSON, L. S., *Some Notes on Averages* . . . . . 30 (Jan. '98) 100–101
275. NELSON, L. S., *Some Notes on Variation* . . . . . 31 (Oct. '99) 459–462
276. NELSON, L. S., *A Stabilized Normal Probability Plotting Technique* . . . . . 21 (Jul. '89) 213–215
277. NELSON, L. S., *Standardization of Shewhart Control Charts* . . . . . 21 (Oct. '89) 287–289
278. NELSON, L. S., *Supplementary Runs Tests for np Control Charts* . . . . . 29 (Apr. '97) 225–227
279. NELSON, L. S., *A Test for Two Groups Automated* . . . . . 30 (Apr. '98) 176–178
280. NELSON, L. S., *Testing the Smallest of a Set of Variances* . . . . . 25 (Apr. '93) 144–148
281. NELSON, L. S., *Test on Early Failures—The Precedence Life Test* . . . . . 25 (Apr. '93) 140–143
282. NELSON, L. S., *A True-False Test for Quality Control and Statistics* . . . . . 28 (Jul. '96) 370–370
283. NELSON, L. S., *Upper Confidence Limits on Average Numbers of Occurrences* . 21 (Jan. '89) 071–072
284. NELSON, L. S., *The Usefulness of Monte Carlo Tests* . . . . . 27 (Oct. '95) 387–389
285. NELSON, L. S., *Using Nested Designs: I. Estimation of Standard Deviations* . . 27 (Apr. '95) 169–171
286. NELSON, L. S., *Using Nested Designs: II. Confidence Limits for Standard Deviations* . . . . . 27 (Jul. '95) 265–267
287. NELSON, P. R., *Multiple Comparisons of Means Using Simultaneous Confidence Intervals* . . . . . 21 (Oct. '89) 232–241
288. NELSON, W., *Hazard Plotting of Left Truncated Life Data* . . . . . 22 (Jul. '90) 230–238
289. NEMBHARD, H. B. AND MASTRANGELO, C. M., *Integrated Process Control for Startup Operations* . . . . . 30 (Jul. '98) 201–211
290. NG, C. H. AND CASE, K. E., *Development and Evaluation of Control Charts Using Exponentially Weighted Moving Averages* . . . . . 21 (Oct. '89) 242–250

P

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292. PALM, A. C., *Tables of Run Length Percentiles for Determining the Sensitivity of Shewhart Control Charts for Averages with Supplementary Runs Rules* . . . . 22 (Oct. '90) 289–298

293. PALM, A. C.; RODRIGUEZ, R. N.; SPIRING, F. A.; AND WHEELER, D. J., *Some Perspectives and Challenges for Control Chart Methods* . . . . . 29 (Apr. '97) 122–127
294. PAPPANASTOS, E. A. AND ADAMS, B. M., *Alternative Designs of the Hodges-Lehmann Control Chart* . . . . . 28 (Apr. '96) 213–223
295. PARK, C. AND REYNOLDS, M. R., JR., *Economic Design of a Variable Sampling Rate $\bar{X}$ Chart* . . . . . 31 (Oct. '99) 427–443
296. PARLAR, M. AND WESOLOWSKY, G. O., *Specification Limits, Capability Indices, and Process Centering in Assembly Manufacture* . . . . . 31 (Jul. '99) 317–325
297. PATEL, J. K. AND SAMARANAYAKE, V. A., *Prediction Intervals for Some Discrete Distributions* . . . . . 23 (Oct. '91) 270–286
298. PEARN, W. L.; KOTZ, S.; AND JOHNSON, N. L., *Distributional and Inferential Properties of Process Capability Indices* . . . . . 24 (Oct. '92) 216–231
299. PFEIFER, P. E., *A General Piecewise Linear Canning Problem Model* . . . . . 31 (Jul. '99) 326–337
300. PIEGORSCH, W. W., *An Introduction to Binary Response Regression and Associated Trend Analyses* . . . . . 30 (Jul. '98) 269–281
301. PIEPEL, G. F., *Screening Designs for Constrained Mixture Experiments Derived from Classical Screening Designs* . . . . . 22 (Jan. '90) 023–033
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Q

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313. QUESENBERRY, C. P., *Geometric Q Charts for High Quality Processes* . . . . . 27 (Oct. '95) 304–315
314. QUESENBERRY, C. P., *On Properties of Binomial Q Charts for Attributes* . . . 27 (Jul. '95) 204–213
315. QUESENBERRY, C. P., *On Properties of Poisson Q Charts for Attributes* . . . . 27 (Oct. '95) 293–303
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317. QUESENBERRY, C. P., *Response* . . . . . 27 (Oct. '95) 333–343
318. QUESENBERRY, C. P., *Screening Outliers in Process Control Regression Data with Uniform Residuals, II* . . . . . 22 (Apr. '90) 087–094
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R

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324. RAMSEY, P. P. AND RAMSEY, P. H., *Simple Tests of Normality in Small Samples* 22 (Oct. '90) 299–309
325. RAZ, T. AND LIITTSCHWAGER, J. M., *Ten Measures of Inspection Performance* 21 (Apr. '89) 081–086
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335. RODRIGUEZ, R. N., *Recent Developments in Process Capability Analysis* . . . . . 24 (Oct. '92) 176–187
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S

343. SACCUCCI, M. S. AND LUCAS, J. M., *Average Run Lengths for Exponentially Weighted Moving Average Control Schemes Using the Markov Chain Approach* 22 (Apr. '90) 154–162
344. SALVIA, A. A. AND LASHER, W. C., *The Power of the F-Test in Two-Factor Nested Experiments* . . . . . 21 (Jan. '89) 020–023
345. SANIGA, E. M., *Joint Statistical Design of $\bar{X}$ and R Control Charts* . . . . . 23 (Apr. '91) 156–162
346. SANIGA, E. M.; DAVIS, D. J.; AND MCWILLIAMS, T. P., *Economic, Statistical, and Economic-Statistical Design of Attribute Charts* . . . . . 27 (Jan. '95) 056–073
347. SCHMIDT, R. L. AND PFEIFER, P. E., *An Economic Evaluation of Improvements in Process Capability for a Single-Level Canning Problem* . . . . . 21 (Jan. '89) 016–019

348. SCHMIDT, R. L. AND PFEIFER, P. E., *Economic Selection of the Mean and Upper Limit for a Canning Problem* . . . . . 23 (Oct. '91) 312–317
349. SCHNEIDER, H.; KASPERSKI, W. J.; AND WEISSFELD, L., *Finding Significant Effects for Unreplicated Fractional Factorials Using the n Smallest Contrasts* 25 (Jan. '93) 018–027
350. SCHNEIDER, H. AND WEISSFELD, L. A., *Interval Estimation Based on Censored Samples from the Weibull Distribution* . . . . . 21 (Jul. '89) 179–186
351. SCHNEIDER, H. AND WEISSFELD, L.A., *Interral Estimation for Censored Accelerated Life Tests Based on the Lognormal Model* . . . . . 21 (Jan. '89) 024–031
352. SCHWERTMAN, N. C. AND RYAN, T. P., *Implementing Optimal Attributes Control Charts* . . . . . 29 (Jan. '97) 099–104
353. SEPPALA, T.; MOSKOWITZ, H.; PLANTE, R.; AND TANG, J., *Statistical Process Control via the Subgroup Bootstrap* . . . . . 27 (Apr. '95) 139–153
354. SHAPIRO, S. S. AND GULATI, S., *Estimating The Mean Of An Exponential Distribution From Grouped Observations* . . . . . 30 (Apr. '98) 107–118
355. SHAPIRO, S. S. AND GULATI, S., *Selecting Failure Monitoring Times for an Exponential Life Distribution* . . . . . 28 (Oct. '96) 429–438
356. SHAPIRO, S. S. AND ZAHEDI, H., *Bernoulli Trials and Discrete Distributions* . 22 (Jul. '90) 193–205
357. SHARP, M. C.; MILLER, S. R.; AND ECONOMOU, J. C., *A General Continuous Sampling Procedure for Resource-Limited Manufacturing Facilities* . . . . . 21 (Jul. '89) 163–173
358. SILVER, E. A. AND ROHLEDER, T. R., *Some Simple Mathematical Aids for Cause-And-Effect Analysis* . . . . . 30 (Jan. '98) 085–092
359. SINGPURWALLA, N. D., *A Probabilistic Hierarchical Classification Model for Rating Suppliers* . . . . . 31 (Oct. '99) 444–454
360. SMITH, W. F., JR. AND BEVERLY, T. A., *Generating Linear and Quadratic Cox Mixture Models* . . . . . 29 (Apr. '97) 211–224
361. SOHN, S. Y., *Growth Curve Analysis Applied to Ammunition Deterioration* . . . 28 (Jan. '96) 071–080
362. SOHN, S. Y. AND PARK, C. J., *Random Effects Linear Models for Both Process Mean and Variance* . . . . . 30 (Jan. '98) 033–039
363. SOLOMON, H. AND STEPHENS, M.A., *Percentage Points for the Cochran Test for Equality of Variances* . . . . . 22 (Jan. '90) 046–056
364. SOUNDARARAJAN, V. AND VIJAYARAGHAVAN, R., *Construction and Selection of Tightened-Normal-Tightened (TNT) Plans* . . . . . 22 (Apr. '90) 146–153
365. SPARKS, R. S. AND EAGLE, A., *Graphical Process Monitoring in the Service Industry—A Case Study* . . . . . 28 (Jan. '96) 099–115
366. SPIRING, F.A., *Assessing Process Capability in the Presence of Systematic Assignable Cause* . . . . . 23 (Apr. '91) 125–134
367. SPIRING, F. A., *A Unifying Approach to Process Capability Indices* . . . . . 29 (Jan. '97) 049–058
368. SPIRING, F. A. AND YEUNG, A. S., *A General Class Of Loss Functions With Industrial Applications* . . . . . 30 (Apr. '98) 152–162
369. SPISAK, A. W., *A Control Chart for Ratios* . . . . . 22 (Jan. '90) 034–037
370. STEINBERG, D. M. AND BURSZTYN, D., *Dispersion Effects in Robust-Design Experiments with Noise Factors* . . . . . 26 (Jan. '94) 012–020
371. STEINER, S. H., *EWMA Control Charts with Time-Varying Control Limits and Fast Initial Response* . . . . . 31 (Jan. '99) 075–086
372. STEINER, S. H. AND HAMADA, M., *Making Mixtures Robust to Noise and Mixing Measurement Error* . . . . . 29 (Oct. '97) 441–450
373. STEPHENSON, W. R., *A Computer Program for Quick and Easy Analysis of Unreplicated Factorials* . . . . . 23 (Jan. '91) 063–067
374. STEPHENSON, W. R.; HULTING, F. L.; AND MOORE, K., *Posterior Probabilities for Identifying Active Effects in Unreplicated Experiments* . . . . . 21 (Jul. '89) 202–212
375. STIMSON, W. A. AND MASTRANGELO, C. M., *Monitoring Serially-Dependent Processes with Attribute Data* . . . . . 28 (Jul. '96) 279–288

376. STOUMBOS, Z. G. AND REYNOLDS, M. R., JR., *Control Charts Applying a Sequential Test at Fixed Sampling Intervals* . . . . . 29 (Jan. '97) 021–040
377. SUICH, R., *The Effects of Inspection Errors on Acceptance Sampling for Nonconformities* . . . . . 22 (Oct. '90) 314–318
378. SULLIVAN, J. H. AND WOODALL, W. H., *A Comparison of Multivariate Control Charts for Individual Observations* . . . . . 28 (Oct. '96) 398–408
379. SULLIVAN, J. H. AND WOODALL, W. H., *A Control Chart for Preliminary Analysis of Individual Observations* . . . . . 28 (Jul. '96) 265–278
380. SUN, D. X. AND WU, C. F. J., *Interaction Graphs for Three-Level Fractional Factorial Designs* . . . . . 26 (Oct. '94) 297–307

T

381. TAGARAS, G., *Economic $\bar{X}$ Charts with Asymmetric Control Limits* . . . . . 21 (Jul. '89) 147–154
382. TAGARAS, G., *A Survey of Recent Developments in the Design of Adaptive Control Charts* . . . . . 30 (Jul. '98) 212–231
383. TANG, K. AND TANG, J., *Design of Screening Procedures: A Review* . . . . . 26 (Jul. '94) 209–226
384. TAYLOR, W. A., *A Program for Selecting Quick Switching Systems* . . . . . 28 (Oct. '96) 473–479
385. TAYLOR, W. A., *Quick Switching Systems* . . . . . 28 (Oct. '96) 460–472
386. TIMM, N. H., *Multivariate Quality Control Using Finite Intersection Tests* . . . 28 (Apr. '96) 233–243
387. TORNG, J. C.-C.; COCHRAN, J. K.; MONTGOMERY, D. C.; AND LAWRENCE, F. P., *Implementing Statistically Constrained Economic EWMA Control Charts* . . . . . 27 (Jul. '95) 257–264
388. TORRES, V. A., *A Simple Analysis of Unreplicated Factorials with Possible Abnormalities* . . . . . 25 (Jul. '93) 183–187
389. TRACY, N. D.; YOUNG, J. D.; AND MASON, R. L., *A Bivariate Control Chart for Paired Measurements* . . . . . 27 (Oct. '95) 370–376
390. TRACY, N. D.; YOUNG, J. C.; AND MASON, R. L., *Multivariate Control Charts for Individual Observations* . . . . . 24 (Apr. '92) 088–095
391. TRICKER, A.; COATES, E.; AND OKELL, E., *The Effect on the $\bar{R}$ Chart of Precision of Measurement* . . . . . 30 (Jul. '98) 232–239
392. TRIETSCH, D., *The Harmonic Rule for Process Setup Adjustment with Quadratic Loss* . . . . . 30 (Jan. '98) 075–084
393. TRINCA, L. A. AND GILMOUR, S. G., *Variance Dispersion Graphs for Comparing Blocked Response Surface Designs* . . . . . 30 (Oct. '98) 314–327
394. TSENG, S.-T.; HAMADA, M.; AND CHIAO, C.-H., *Using Degradation Data to Improve Fluorescent Lamp Reliability* . . . . . 27 (Oct. '95) 363–369
395. TSENG S.-T. AND WU, T.-Y., *Selecting the Best Manufacturing Process* . . . . 23 (Jan. '91) 053–062
396. TSUNG, F.; SHI, J.; AND WU, C. F. J., *Joint Monitoring of PID-Controlled Processes* . . . . . 31 (Jul. '99) 275–285
397. TURIEL, T. P. *A FORTRAN Computer Program to Determine Sample Sizes and Generate Power Curves for Completely Randomized and Randomized Complete Block Designs* . . . . . 21 (Oct. '89) 277–286

U

398. ULLMAN, N. R., *The Analysis of Means (ANOM) for Signal and Noise* . . . . . 21 (Apr. '89) 111–127

V

399. VAUGHAN, T. S. AND PETERS, M. H., *Economic Design of Fraction Nonconforming Control Charts with Multiple State Changes* . . . . . 23 (Jan. '91) 032–043
400. VINING, G. G., *A Compromise Approach To Multiresponse Optimization* . . . . 30 (Oct. '98) 309–313

401. VINING, G. G., *A Computer Program for Generating Variance Dispersion Graphs* 25 (Jan. '93) 045–058
402. VINING, G. G. AND BOHN, L. L., *Response Surfaces for the Mean and Variance Using a Nonparametric Approach* . . . 30 (Jul. '98) 282–291
403. VINING, G. G. AND MYERS, R. H., *Combining Taguchi and Response Surface Philosophies: A Dual Response Approach* . . . 22 (Jan. '90) 038–045
404. VINING, G. G. AND REYNOLDS, M. R., JR., *Multi-Level Sampling Interval Approach to Control Charts* . . . 29 (Oct. '97) 418–428
405. VINING, G. G. AND SCHAUB, D., *Experimental Designs for Estimating Both Mean and Variance Functions* . . . 28 (Apr. '96) 135–147
406. VIVEROS, R. AND BALAKRISHNAN, N., *Statistical Inference from Start-Up Demonstration Test Data* . . . 25 (Apr. '93) 119–130

W

407. WADE, M. R. AND WOODALL, W. H., *A Review and Analysis of Cause-Selecting Control Charts* . . . 25 (Jul. '93) 161–169
408. WALKER, E.; PHILPOT, J.W.; AND CLEMENT,J., *False Signal Rates for the Shewhart Control Chart with Supplementary Runs Rules* . . . 23 (Jul. '91) 247–252
409. WANG, C. M. AND LAM, C. T., *Confidence Limits for Proportion of Conformance* . . . 28 (Oct. '96) 439–445
410. WANG, Y.; LIN, D. K. J.; AND FANG, K.-T., *Designing Outer Array Points* . 27 (Jul. '95) 226–241
411. WARDELL, D.G.; MOSKOWITZ, H.; AND PLANTE, R. D., *Run Length Distributions of Residual Control Charts for Autocorrelated Processes* . . . 26 (Oct. '94) 308–317
412. WATTS, D. G., *Explaining Power Using Two-Level Factorial Designs* . . . 29 (Jul. '97) 305–306
413. WATTS, D. G., *Understanding Canonical Analysis* . . . 27 (Jan. '95) 040–044
414. WELCH, W. J.; YU, T.-K.; KANG, S. M.; AND SACKS, J., *Computer Experiments for Quality Control by Parameter Design* . . . 22 (Jan. '90) 015–022
415. WHITE, C. H. AND KEATS, J. B., *ARLs and Higher-Order Run-Length Moments for the Poisson CUSUM* . . . 28 (Jul. '96) 363–369
416. WILLEMAIN, T. R. AND RUNGER, G. C., *Designing Control Charts Using an Empirical Reference Distribution* . . . 28 (Jan. '96) 031–038
417. WILLIAMS, W. W.; LOONEY, S. W.; AND PETERS, M. H., *Improved Curtailed Sampling Plans for np Control Charts* . . . 22 (Apr. '90) 118–127
418. WOLFINGER, R. D., *Tolerance Intervals for Variance Component Models Using Bayesian Simulation* . . . 30 (Jan. '98) 018–032
419. WOODALL, W. H., *Control Charts Based on Attribute Data: Bibliography and Review* . . . 29 (Apr. '97) 172–183
420. WOODALL, W. H.; CROWDER, S. V.; AND WADE, M. R., *Discussion* . . . 27 (Oct. '95) 328–332
421. WOODALL, W H. AND MONTGOMERY, D C., *Research Issues and Ideas in Statistical Process Control* . . . 31 (Oct. '99) 376–386

Z

422. ZIMMER, W. J.; KEATS, J. B.; AND WANG, F. K., *The Burr XII Distribution in Reliability Analysis* . . . 30 (Oct. '98) 386–394
423. ZIMMER, W. J.; WANG, Y.; AND PATHAK, P. K., *Log-Odds Rate and Monotone Log-Odds Rate Distributions* . . . 30 (Oct. '98) 376–385

SUBJECT INDEX

A

Accelerated Life Tests 351
Acceptable Quality Level 126, 127
Acceptance Sampling 5, 66, 135, 162, 170, 207, 239, 364, 377, 384, 385
Accuracy 34
Active Control Policy 201
Adaptive Control Scheme 75, 128, 308, 309, 382
Adjusted Average Time to Signal 11, 75, 76, 78
Aliasing 50, 139, 228
Analysis of Means 231, 287, 373, 398
Analysis of Ranges 398
Analysis of Variance 14, 52, 53, 231, 240, 280, 397
Analysis of Variation 285, 286
Approximation 143, 271, 272, 279, 358
Arcsin Transformation 276
ASN Function 219, 222
Attributes Sampling Plans 239, 364
Attributes Control Charts 147, 165, 169, 231, 277, 313, 314, 315, 328, 342, 346, 325, 419
Attributes Data 263, 375, 419
Augmented Box Plots 69
Autocorrelated Observations 194, 195, 203, 231, 289
Autocorrelated Process 152, 192, 201, 331, 396, 411
Autocorrelation 1, 227
Automated Laboratory Instruments 68
Autoregressive First Order Process 10
Autoregressive Integrated Moving Average Process 198, 225, 231, 327
Autoregressive Models 14, 186
Autoregressive Moving Average Model 194, 195
Average Outgoing Quality 357
Average Outgoing Quality Limit 26, 127
Average Run Length 2, 17, 25, 36, 37, 56, 59, 70, 85, 86, 88, 99, 118, 119, 120, 121, 122, 143, 161, 174, 194, 195, 205, 231, 232, 290, 294, 308, 309, 310, 312, 331, 338, 339, 352, 371, 376, 391, 411, 415, 416
Averages 274
Average Sample Number 417
Average Time to Signal 77, 309, 326, 327

B

Bayesian Classification Rule 359
Bayesian Methods 13, 45, 63, 124, 207, 362
Bayesian Sampling 66
Bayesian Plots 374
Bayes' Theorem 374
Bernoulli 328, 356
Beta-Binomial Distribution 356
Bias 275, 369
Binomial Distribution 36, 148, 217, 246, 250, 263, 264, 278, 300, 314, 319, 334, 356
Binomial Selection Problems 116
Bivariate Normal Distribution 34
Bivariate Response 14
Blending 73, 360
Blocking 30, 102, 153, 393
Bootstrap Methods 115, 160, 164, 335, 353
Box-Behnken Designs 393
Box Plots 47, 69
Box-Meyer Plots 374

C

Calibration 18, 68
Canning Problem 299, 347, 348
Capability Indices 64, 115, 132, 153, 163, 185, 188, 244, 296, 298, 335
Capability Maturity Model 359
Cause Selecting Control Charts 212
c Charts 320
Censored Data 51, 125, 135, 171, 173, 288, 349, 350, 351
Central Composite Designs 179, 197, 213, 393
Change Point 58
Chi-Squared Distribution 86, 130, 146, 231, 310, 338
C-Linear Association 14
Clustering 241, 249, 279, 284
Cochran Statistic 363
Coefficient of Variation 275
Coherent System 358
Collinearity 205, 206, 230
Computer Experiment 80, 254, 284, 345, 414
Confidence Intervals 52, 53, 89, 148, 245, 253, 270, 286, 300, 337, 350, 406, 409
Confidence Limits 20, 115, 132, 185, 254, 268, 283, 335
Confounding 23, 167, 333
Constrained Least Squares 124
Constrained Optimization 191, 358, 403
Constrained Simplex 181
Consumer Risk 19, 66, 94
Continuous Loss Function 113
Continuous Process 201
Continuous Sampling 26, 126, 218, 357
Control Charts 1, 6, 12, 36, 60, 68, 77, 84, 111,

150, 188, 216, 227, 231, 243, 258, 278, 282, 294, 308, 309, 319, 321, 336, 339, 345, 421
Control Limits 19, 128, 164, 243, 278, 282, 291, 353, 417
Control Scheme 339, 343
Correlated Data 58, 84, 231, 255, 256, 257, 327, 375
Count Data 95, 148, 169
C_p-Criterion 206
Critical Values 241, 249, 251, 272, 278, 281
Cumulative Sum 58, 196, 305, 328, 371
Cumulative Sum Control Charts 39, 59, 85, 118, 121, 122, 143, 145, 180, 231, 232, 313, 315, 340, 404, 415

D

Data Analysis 22, 28, 47, 137, 237
Design Efficiencies 189, 238
Design Generators 30, 31
Design of Control Charts 174, 258, 273, 277, 352
Design of Experiments 24, 29, 43, 81, 105, 140, 153, 166, 187, 199, 230, 237, 303, 304, 306, 333
Demerit Rating System 165
Desirability Function 93, 400
Deviance 300
Differential Equations 119
Directional Data 14
Discrete Distributions 169, 356
D-Optimality 13, 213, 214, 238, 393, 405

E

Economic Control Charts 62, 220, 221, 229, 231, 346, 387
Economic Design 54, 150, 159, 221, 295, 322, 323, 346, 381, 383, 399, 417
Economic Selection 299, 348
Embedding 72
Empirical Bayes 207
Engineering Process Control 44, 91, 158, 198, 225, 231, 289
Equality of Variance Tests 363
Estimation 95, 243, 271, 282, 285, 286, 354
Expected Cost Model 417
Expected Values 298
Experimental Design 213, 398
Experimentation 41
Exponential Distribution 21, 118, 122, 123, 180, 355
Exponentially Weighted Moving Average 58, 99, 133, 155, 227, 232, 289, 290, 343, 371
Exponentially Weighted Moving Average Control Charts 6, 25, 36, 37, 85, 180, 194, 195, 229, 231, 310, 313, 315, 326, 387
Extreme Value Control Charts 12

F

Factorial Designs 32, 72, 74, 102, 156, 171, 214, 228, 370, 373, 374, 412
Failure Rate 423
Fast Initial Response 59, 143, 196, 371
Finite Population 114
First Order Autoregressive Models 194, 195
Foldover 15, 50
Fourth Moment 324
Fractional-Factorial Designs 15, 27, 28, 30, 31, 91, 102, 138, 167, 187, 193, 200, 228, 302, 333, 349, 394, 410

G

Gaussian Elimination 161
Gauging 100
Generalized Least Squares 189
Generalized Likelihood Ratio 58
Generalized Linear Models 129, 137, 235, 237
Generalized Sampling Plans 239
Geometric Distribution 169, 356
Geometric Mean 274
Goodness-of-Fit Methods 61, 110, 206, 242, 276, 335, 422
G-Optimality 238
Graphical Methods 22, 23, 24, 67, 134, 136, 199, 255, 288, 335
Grouped Data 135, 162, 232, 279, 354, 383

H

Half-Normal Plots 28
Hard to Change Design Variables 235
Harmonic Mean 274
Hazard Function 288, 422
Head Start 120, 196
Heterogenous Variance 213
Hierarchical Experiments 249, 344
Hotelling's T^2 Statistic 144, 209, 210, 211, 212, 231, 378, 386, 407
Hypergeometric Distribution 162, 219, 264
Hypothesis Testing 52, 61, 171, 281, 245, 262, 263, 266, 284, 349, 355

I

Individuals Control Charts 37, 180
Inspection 26, 157, 170, 283, 311, 325

Inspection Costs 101
Inspection Error 162, 377
Integral Control 158
Integral Equations 35, 82, 83, 120, 194, 195
Intensity Function 330
Interactions 45, 74, 139, 140, 333, 370, 380
Interval Estimation 215, 351
Investigation 41, 43
I-Optimality 213
ISO Standards 231, 240

J

Johnson System 65, 307

K

Kernel Density 335

L

Lagrangian Interpolation 256, 261
Least Squares Estimation 4, 237
Likelihood Ratio 184, 395
Limit Numbers 49
Limit Quality Level 126
Linear Graphs 167, 380
Location Parameter 83
Log-Gamma Distribution 83
Logistic Regression 300
Log Logistic Distribution 423
Lognormal Distribution 5, 291, 351
Log-Odds Rate 423
Lomedian 68
Loss Functions 8, 48, 163, 298, 368, 372, 400
Low Level Defects 196

M

Markov Chain 26, 49, 56, 57, 76, 161, 295, 343, 371, 406
Matched Logarithmic Values 67
Maximum Likelihood 46, 125, 137, 173, 178, 184, 198, 237, 379, 422
Maximum Likelihood Estimation 4, 406
Mean 274
Mean Squared Error 44, 201, 225
Mean Value Function 4
Measurement Error 18, 103, 151, 252, 418
Measurements Over Time 69
Medians 46, 55, 67, 243, 258
Membership Function 179
Minimal Cut Set 106
Minimal Path Set 106
Minimum-Aberration 15, 380
Minimum Expected Loss 113
Mistake Proofing 101
Mixed Models 100, 418
Mixture Components 301
Mixture Experiments 13, 72, 73, 181, 230, 303, 304
Mode 274
Model Specification 212
Moment Estimation 3, 184, 406, 415
Monte Carlo Simulation 19, 58, 61, 98, 272, 284, 406
Moving Averages 243, 282
Moving Range 2, 6, 46, 84, 258, 331, 336, 379
Multi-Component Constraints 181
Mulitnomial Distribution 354, 356
Multiple Comparisons 55, 241, 249, 287, 300
Multiple Responses 8, 71, 89, 92, 131, 191, 235, 405
Multivariate Analysis 47, 183
Multivariate Capability Indices 298
Multivariate Control Charts 35, 130, 144, 183, 209, 210, 211, 212, 231, 305, 310, 338, 378, 386, 389, 407
Multivariate Normal Distribution 98, 243
Multivariate Quality Control 146, 231, 305, 389, 390

N

Negative Binomial Distribution 95, 169, 356
Nested Experiments 12, 140, 240, 285, 286, 344
Noise 398
Nonconforming 26, 149, 283, 320, 417
Nonnormality 58, 244
Nonparametric 160, 168, 266, 270
Nonparametric Control Chart 7
Nonparametric Test 55, 133, 247, 255, 266
Normal Approximation 262, 263, 268, 337
Normal Distribution 117, 123, 132, 216, 243, 248, 251, 270, 276, 282, 351
Normality 49, 242, 244
np Control Chart 399

O

Odds Ratio 217
OC Function 219, 222
Off-Line Quality Control 414
One-Sample Tests 262, 263
One-Way Layout 55, 397
Operating Characteristic Curves 337, 385
Optimal Experimental Design 301, 302
Optimization 71, 90, 92, 93, 191, 306, 402

Optimum Target Value 16, 38, 151, 223, 311, 342
Orthogonal Arrays 15, 166, 167, 176, 333, 380, 410
Orthogonal Decomposition 212
Outgoing Quality 218
Outliers 17, 46, 318, 378, 388

P

Pairwise Comparisons 287
Parameter Design 204, 236, 306, 414
Pareto Chart 160, 175
Parts-Per-Million Nonconforming Items 216, 248
p-Charts 39, 282, 328
Pentamean 67
Percentiles 65, 307
Performance Measures 63, 325, 410
Plackett-Burman Designs 51, 81, 139, 301, 302
Poisson Approximation 337
Poisson Distribution 36, 119, 122, 148, 262, 263, 330, 334, 356
Poisson Process 33, 118, 329, 332
Pooling 28
Posterior Probabilities 45, 374
Power 200, 262, 263, 281, 324, 344, 397
Power Law Process 332
Precision 34, 107
Prediction 21, 73, 105, 160, 178, 205, 206, 218, 236, 393
Principal Components 183, 231, 240, 305, 389
Prior Distribution 157
Probability 117, 218, 245
Probability Plots 110, 276, 422
Process Capability 47, 48, 132, 244, 335, 366, 367, 409
Process Capability Indices 366, 367
Process Control 38, 44, 54, 150, 221, 223, 231, 243, 318, 339, 346, 399
Process Improvement 62, 358
Process Optimization 8, 16, 38, 223, 311
Process Quality 368
Process Variability 59, 107, 129, 201, 203, 236
Proportion 328
Proportion Nonconforming 243, 282
Pseudo-Standard Deviation 67

Q

Q Charts 312, 313, 314, 315, 316
Quadratic Loss Function 392
Quality 348, 419
Quality Control 12, 75, 164, 203, 309, 362
Quality Improvement 62, 97, 149, 176, 187, 199, 347, 358
Quality Loss Function 204
Quality Management 175, 359
Quality Selection 299
Quantiles 65, 307

R

Random Effects 18, 52, 176, 178, 361, 362, 418
Randomization 217, 243, 260, 266, 270
Randomized Complete Block Design 397
Range 258, 271, 275, 282, 398
Ranks 133
Rates 274
Ratio Estimates 233, 369
Rational Subgroups 244
R-Charts 391
Rectifying Inspection 127, 377
Regression Analysis 58, 124, 138, 140, 144, 205, 206, 211, 237, 266, 318, 361, 375, 407
Reliability 20, 33, 51, 106, 134, 135, 361, 394
REML 418
Repairable Systems 33, 330
Repeatability 53, 94, 100
Reproducibility 53, 94, 100
Residuals 137, 194, 195, 318, 340, 371
Resolution 15, 29, 30, 50, 333
Response Model 63, 217
Response Surface Methodology 23, 41, 43, 71, 74, 81, 89, 90, 92, 93, 105, 189, 191, 214, 236, 238, 303, 360, 400, 403, 405, 413, 414
Robust Designs 8, 176, 235, 236, 362, 370, 372
Robustness 11, 41, 133, 145, 329
Run Length 88, 121, 133, 292, 411
Runs Rules 57
Runs Test 258, 278, 408

S

Sample Estimates 325
Sample Size 20, 116, 262, 263, 270, 312, 334
Sample Standard Deviation 84
Sampling 136, 147, 252, 260, 283, 355
Sampling by Attributes 219, 222
Sampling Plan Costs 239
Scale Parameter 83
S Control Charts 86
Screening Experiments 43, 45, 131, 139, 197, 318, 383
Scoring 359
Sensitivity Analysis 82, 120, 220
Sequential Experimentation 105, 228, 246, 250
Sequential Test 219, 222
Serial Correlation 257

Shapiro-Wilk Test 65, 123, 307, 324
Shewhart Control Charts 56, 57, 79, 85, 130, 133, 164, 180, 194, 195, 231, 232, 244, 259, 277, 291, 292, 313, 315, 326, 339, 340, 353, 369, 377, 407, 408, 416
Shewhart EWMA 343
Short Runs 319, 320, 321
Signal 398
Signal-to-Noise Ratio 129, 204
Significance Tests 148, 243, 245, 246, 247, 251, 253, 256, 266, 272, 279, 280, 281, 282, 284
Simulation 11, 193, 340, 391, 409
Simultaneous Inference 16, 34, 146, 287, 405
Singular Value Decomposition 205
Skewed Distribution 19, 61, 67, 243, 282
Slack Variable 304
Smoothing Functions 402
Split-Plot Designs 135, 189
Stability Criteria 244, 334
Staggered Nested Designs 240
Standard Deviation 243, 254, 271, 275, 282, 285, 286
Start-Up Processes 320, 321
Stationary Probability 49
Statistical Graphics 369
Statistical Process Control 1, 17, 25, 39, 58, 59, 62, 75, 76, 77, 78, 85, 91, 98, 99, 101, 117, 119, 128, 147, 152, 155, 157, 158, 164, 165, 169, 174, 175, 183, 188, 192, 225, 231, 243, 282, 289, 294, 296, 308, 309, 310, 326, 327, 328, 336, 338, 340, 353, 365, 367, 375, 376, 378, 381, 382, 396, 404, 408, 416, 419, 421
Statistical Quality Control 147, 175, 421
Steepest Ascent 43
Stem-and-Leaf 69
Structure Function 80, 106
Student's t 270
Successive Differences 68

T

Taguchi Methods 28, 50, 51, 166, 167, 197, 306, 370, 372, 374, 402, 405, 414
Target Value 48
T^2 Control Chart 146, 209, 210, 231, 386, 390
t-Distribution 257
Tests for Special Causes 257
Test for Two Groups 274, 281
Three-Level Factorials 179
3-Parameter Weibull 215
Threshold Parameter 215
Time Series 22, 396
Time Series Analysis 1, 17, 152, 192, 198, 231, 340
Time Series Modeling 227, 158
Tolerance Limits 58, 103, 218, 236
Transformations 32, 131, 244, 256, 261
Trends 46, 56, 300
Trimean 67
Truncated Data 168, 288
Type I Error 324, 408

U

u Charts 320
Unbiasedness 298
Unsuccessful Differences 68

V

Variable Parameters Control Charts 75, 78
Variable Sample Size 76, 77, 79, 295, 308, 309, 339, 376
Variable Sampling Intervals 25, 76, 77, 295, 308, 309, 323, 326, 327, 376
Variable Selection 206
Variables Control Chart 11, 128, 231, 271, 273, 277, 315, 316
Variables Sampling Plan 127, 385
Variance 271, 275, 298
Variance Components 18, 52, 97, 100, 156, 178, 279, 285, 286
Variation Reduction 3, 186

W

Weibull Distribution 20, 134, 173, 216, 220, 248, 291, 350, 354
Weibull Process 4, 329, 330, 332

X

X Charts 248, 312, 331, 379
$\bar{X}$ Control Charts 6, 8, 16, 19, 62, 78, 88, 159, 312, 323, 326, 327, 381
$\bar{X}$, R Charts 322

Z

Zero Defectives 207
Zone Control Chart 161

COMPUTER PROGRAMS

	Vo.	(Mo. Yr.)	Pages
BODDEN, K. M. AND RIGDON, S. E., *A Program for Approximating the In-Control ARL for the MEWMA Chart*	31	(Jan. '99)	120–123
CHAMP, C. W. AND WOODALL, W. H., *A Program to Evaluate the Run Length Distribution of a Shewhart Control Chart with Supplementary Runs Rules*	22	(Jan. '90)	068–073
COSTA, A. F. B., *AATS for the $\bar{X}$ Chart with Variable Parameters*	31	(Oct. '99)	455–458
CROSIER, R. B., *FORTRAN Programming Techniques*	23	(Oct. '91)	348–354
DAVIS, R. B., *Designing S-Charts with Two Average Run Length Constraints*	31	(Apr. '99)	246–248
DHAVALE, D. G., *Computational Approaches to Estimating Negative Binomial Parameters from Count Data*	21	(Jan. '89)	051–064
DEL CASTILLO, E., *Evaluation of Run Length Distribution for $\bar{X}$ Charts with Unknown Variance*	28	(Jan. '96)	116–122
DEL CASTILLO, E.; FAN, S.-K.; AND SEMPLE, J., *The Computation of Global Optima in Dual Response Systems*	29	(Jul. '97)	347–353
EBRAHIMI, N. AND DUNNIGAN, K., *Two Programs for System Reliability Computation*	30	(Jan. '98)	093–099
GAN, F. F., *Computing the Percentage Points of the Run Length Distribution of an Exponentially Weighted Moving Average Control Chart*	23	(Oct. '91)	359–365
GAN, F. F., *The Run Length Distribution of a Cumulative Sum Control Chart*	25	(Jul. '93)	205–215
GAN, F. F. AND CHOI, K. P., *Computing Average Run Lengths for Exponential CUSUM Schemes*	26	(Apr. '94)	134–143
GAN, F. F. AND KOEHLER, K. J., *A Goodness-of-Fit Test Based on $P-P$ Probability Plots*	24	(Apr. '92)	096–102
GUIRGUIS, G. H. AND RODRIGUEZ, R.N., *Computation of Owen's Q Function Applied to Process Capability Analysis*	24	(Oct. '92)	236–246
HAMADA, M. AND TSE, S. K., *The Existence of Maximum Likelihood Estimates from Designed Experiments*	28	(Apr. '96)	244–254
HAMILTON, M.D., *Average Run Lengths of Exponentially Weighted Moving Average Control Charts for Monitoring a Process Standard Deviation*	24	(Jan. '92)	044–050
HEYES, G. B., *A Computer Program for Comparison of Multiple Poisson Means*	22	(Jul. '90)	239–244
JARAIEDI, M. AND ZHUANG, Z., *Determination of Optimal Design Parameters of $\bar{X}$ Charts When there is a Multiplicity of Assignable Causes*	23	(Jul. '91)	253–258
JIN, C. AND DAMS, R. B., *Calculation of Average Run Lengths for Zone Control Charts with Specified Zone Scores*	23	(Oct. '91)	355–358
KASPERSKI, W. J.; SCHNEIDER, H.; AND JOHNSON, K. L., *Analyzing Unreplicated Factorials Using the n Smallest Contrasts*	27	(Oct. '95)	377–386
KEATS, J. B.; LAWRENCE, F. P; AND WANG, F. K., *Weibull Maximum Likelihood Parameter Estimates with Censored Data*	29	(Jan. '97)	105–110
LUCEÑO, A., *Choosing the EWMA Parameter in Engineering Process Control*	27	(Apr. '95)	162–168
MCSHANE, L. M. AND TURNBULL, B. W., *New Performance Measures for Continuous Sampling Plans Applied to Finite Production Runs*	24	(Jul. '92)	153–161
MCWILLIAMS, T. P., *Acceptance Sampling Plans Based on the Hypergeometric Distribution*	22	(Oct. '90)	319–327
MCWILLIAMS, T. P., *Economic, Statistical, and Economic-Statistical $\bar{X}$ Chart Designs*	26	(Jul. '94)	227–238
MCWILLIAMS, T. P., *Operating Characteristic and Average Sample Number Functions for Attribute Based Sequential Test Plans*	21	(Apr. '89)	128–135
NAIK, D. N. AND KHATTREE, R., *A Computer Program to Estimate Variance Components in Staggered Nested Designs*	30	(Jul. '98)	292–297
NELSON, L. S., *Construction and Evaluation of Closed Sequential Sign Tests*	25	(Apr. '93)	131–139

	Vo.	(Mo. Yr.)	Pages
NELSON, L. S., *Sample Sizes for Confidence Intervals with Specified Lengths and Tolerances*	26	(Jan. '94)	054–063
POLANSKY, A. M.; CHOU, Y.-M.; AND MASON, R. L., *An Algorithm for Fitting Johnson Transformations to Non-normal Data*	31	(Jul. '99)	345–350
PRABHU, S. S.; MONTGOMERY, D. C.; AND RUNGER, G. C., *A Design Tool to Evaluate Average Time to Signal Properties of Adaptive $\bar{X}$ Charts*	27	(Jan. '95)	074–083
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RAHIM, M. A., *Determination of Optimal Design Parameters of Joint $\bar{X}$ and R Charts*	21	(Jan. '89)	065–070
RAHIM, M. A., *Economic Design of $\bar{X}$-Control Charts Assuming Weibull In-Control Times*	25	(Oct. '93)	296–305
RIGDON, S. E.; MA, X.; AND BODDEN, K. M., *Statistical Inference for Repairable Systems Using the Power Law Process*	30	(Oct. '98)	395–400
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SANIGA, E. M.; DAVIS, D. J.; AND MCWILLIAMS, T. P., *Economic, Statistical, and Economic-Statistical Design of Attribute Charts*	27	(Jan. '95)	056–073
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WARDELL, D.G.; MOSKOWITZ, H.; AND PLANTE, R. D., *Run Length Distributions of Residual Control Charts for Autocorrelated Processes*	26	(Oct. '94)	308–317
WHITE, C. H. AND KEATS, J. B., *ARLs and Higher-Order Run-Length Moments for the Poisson CUSUM*	28	(Jul. '96)	363–369

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	Vo.	(Mo. Yr.)	Pages
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NELSON, L. S., *The Anderson-Darling Test for Normality*	30	(Jul. '98)	298–299
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NELSON, L. S., *Interpolation for Intermediate Significance Levels*	28	(Apr. '96)	255–256
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NELSON, L. S., *Randomization Test for Linear Correlation/Regression*	29	(Jul. '97)	354–356
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B121. *Introduction to Time Series* by W. A. Fuller . . . . . C. MASTRANGELO 31 (Jan. '99) 128–129
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B127. *JMP Start Statistics* by J. Sall and A. Lehman . . . . . K. A. F. COPELAND 28 (Oct. '96) 484–484
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B138. *Measurement Error Models* by W. A. Fuller . . . . . R. F. GUNST 21 (Oct. '89) 294–295
B139. *Methods and Applications of Linear Models* by R. R. Hocking . . . . . E. S. VALEROSO 30 (Jul. '98) 302–303
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B147. *Modern Industrial Statistics* by R. S. Kenett and S. Zacks . C. R. LOVELACE 31 (Jul. '99) 358–359
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B185. *Quality* by D. C. S. Summers . . . . . D. SCHAUB 31 (Jan. '99) 129–130
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B201. *The Quality Toolbox* by N. R. Tague . . . . . J. J. BORKOWSKI 27 (Oct. '95) 391–392
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B205. *Readings in Decision Analysis* by S. French . . . . . P. S. PULAT 22 (Apr. '90) 168–168
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B213. *Reliability for the Technologies* by L. A. Doty . . . . . L. LEEMIS 21 (Jan. '89) 079–080
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B221. *Resampling: The New Statistics* by J. L. Simon . . . . . C. B. PHEATT 25 (Oct. '93) 319–321
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B225. *Robust Design and Analysis for Quality Engineering* by S. H. Park . . . . . J. R. SIMPSON 30 (Apr. '98) 182–184
B226. *Robust Regression; Analysis and Applications* by K. D. Lawrence and J. L. Arthur . . . . . G. G. VINING 23 (Apr. '91) 175–176
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B233. *Sensitivity Analysis in Linear Regression* by S. Chatterjee and A. S. Hadi . . . . . J. G. VOELKEL 22 (Jul. '90) 250–250
B234. *Sequential Simplex Optimization* by F. H. Walters . . . . . L. S. NELSON 24 (Jul. '92) 164–165
B235. *Short Run SPC* by D. J. Wheeler . . . . . J. S. DOWD 25 (Jul. '93) 224–225
B236. *Simulation for Decision Making* by A. Thesen and L. E. Travis . . J. J. SWAIN 25 (Jul. '93) 225–226
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B239. *SPC and Continuous Improvement* by M. Owen . . . . . D. J. DEPRIEST 23 (Apr. '91) 175–175
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B242. *SPC for the Rest of Us; A Personal Path to Statistical Process Control* by H. Pitt . . . . . J. S. DOWD 26 (Jul. '94) 243–244
B243. *SPC Tools for Operators* by J. T. Burr . . . . . L. C. VANCE 23 (Apr. '91) 177–178
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B246. *The Statistical Analysis of Compositional Data* by J. Aitchison . . C. MCCALL 22 (Apr. '90) 170–171
B247. *Statistical Analysis of Reliability and Life Testing Models: Theory and Methods* by L. J. Bain and M. Englehardt . . . . . W. S. GRIFFITH 25 (Apr. '93) 159–159
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B252. *Statistical Control by Monitoring and Feedback Adjustment* by G. Box and A. Luceño . . . . . T. P. RYAN 30 (Oct. '98) 409–413
B253. *Statistical Design and Analysis of Experiments* by R. L. Mason, R. F. Gunst, and J. L. Hess . . . . . L. S. NELSON 22 (Apr. '90) 166–166
B254. *Statistical Design and Analysis of Industrial Experiments* by S. Ghosh . . . . . G. G. VINING 23 (Oct. '91) 373–373
B255. *Statistical Distributions* by M. Evans, N. Hastings, and B. Peacock . . . . . K. A. F. COPELAND 27 (Jan. '95) 094–095
B256. *Statistical Factor Analysis and Related Methods* by A. Basilevsky . . . . . R. D. DEVEAUX 28 (Jan. '96) 132–132
B257. *Statistical Intervals: A Guide for Practitioners* by G. J. Hahn and W. Q. Meeker . . . . . W. M. BOWEN 24 (Jul. '92) 170–172
B258. *Statistically Speaking, A Dictionary of Quotations* by C. C. Gaither and A. E. Cavazos-Gaither . . . . . L. S. NELSON 29 (Apr. '97) 232–233
B259. *Statistical Methodology in the Pharmaceutical Sciences* by D. A. Berry . . . . . S. J. RUBERG 22 (Oct. '90) 331–332
B260. *Statistical Methods* by G. W. Snedecor and W. G. Cochran . . N. R. FARNUM 22 (Jul. '90) 252–253

B261. *Statistical Methods: A Geometric Primer* by D. J. Saville and G. R. Wood . . . . . K. A. F. COPELAND 28 (Oct. '96) 487–487
B262. *Statistical Methods for Engineers* by G. G. Vining . . . . . L. ZIMMER 31 (Apr. '99) 255–256
B263. *Statistical Methods for Engineers and Scientists, 3rd ed.* by B. M. Bethea, B. S. Duran, and T. L. Boullion . . . . . L. S. NELSON 27 (Oct. '95) 392–393
B264. *Statistical Methods for Industrial Process Control* by D. Drain . . . . . J. D. STANLEY 30 (Jul. '98) 303–305
B265. *Statistical Methods for Physical Science* edited by J. L. Stanford and S. B. Vardeman . . . . . K. A. F. COPELAND 27 (Apr. '95) 180–181
B266. *Statistical Methods for Quality* by I. Miller and M. Miller . . . . . M. R. WADE 28 (Jan. '96) 132–133
B267. *Statistical Methods for Quality Improvement* by T. P. Ryan . . . L. S. NELSON 22 (Jan. '90) 079–080
B268. *Statistical Methods for Reliability Data* by W. Q. Meeker and L. A. Escobar . . . . . J. B. KEATS 31 (Oct. '99) 466–468
B269. *Statistical Methods for Testing, Development, and Manufacturing* by F. W. Breyfogle . . . . . L. S. NELSON 25 (Jul. '93) 228–230
B270. *Statistical Methods for the Process Industries* by W. H. McNeese and R. A. Klein . . . . . L. S. NELSON 25 (Oct. '93) 322–324
B271. *Statistical Methods in Engineering and Manufacturing* by J. Brown . . . . . L. S. NELSON 26 (Jan. '94) 074–076
B272. *Statistical Methods in Engineering and Quality Assurance* by P. W. M. John . . . . . J. G. VOELKEL 24 (Jul. '92) 165–166
B273. *Statistical Methods in Reliability Theory and Practice* by B. D. Bundy . . . . . A. C. COHEN 25 (Apr. '93) 153–154
B274. *Statistical Methods of Quality Assurance* by H.-J. Mittag and H. Rinne . . . . . L. S. NELSON 27 (Jan. '95) 095–096
B275. *Statistical Methods: The Geometric Approach* by D. J. Saville and G. R. Wood . . . . . C. H. MCCALL 25 (Jan. '93) 074–075
B276. *Statistical Models for Ordinal Variables* by C. C. Clogg and E. S. Shihadeh . . . . . J. D. RICHARDS 27 (Oct. '95) 394–394
B277. *Statistical Principles of Research Design and Analysis* by R. O. Kuehl . . . . . L. B. HARE 27 (Jan. '95) 096–097
B278. *Statistical Problem Solving* by W. E. Carr . . . . . L. S. NELSON 25 (Jul. '93) 230–231
B279. *Statistical Process Control: An IFS Executive Briefing* by J. Mortimer . . . . . J. S. DOWD 21 (Oct. '89) 292–293
B280. *Statistical Process Control for Quality Improvement* by J. R. Thompson and J. Koronacki . . . . . L. S. NELSON 25 (Oct. '93) 324–324
B281. *Statistical Process Control in Manufacturing* by J. B. Keats and D. C. Montgomery . . . . . B. N. RAMEY 26 (Jan. '94) 076–077
B282. *Statistical Process Control in Manufacturing Practice* by F. W. Kear . . . . . K. A. F. COPELAND 30 (Jul. '98) 305–306
B283. *Stastical Process Control Made Easy* by P. McReynolds . . . . C. R. LOVELACE 29 (Apr. '97) 231–232
B284. *Statistical Process Control Methods for Long and Short Runs* by G. K. Griffith . . . . . L. S. NELSON 28 (Jul. '96) 372–374
B285. *Statistical Process Control: Theory and Practice* by G. B. Wetherill and D. W. Brown . . . . . J. S. DOWD 24 (Apr. '92) 109–110
B286. *Statistical Quality Control, 6th ed.* by E. L. Grant and R. S. Leavenworth . . . . . L. S. NELSON 23 (Jul. '91) 266–267
B287. *Statistical Quality Control* by E. L. Grant and R. S. Leavenworth . . . . . R. L. EDGEMAN 29 (Jul. '97) 365–366
B288. *Statistical Quality Control* by J. Ledolter and C. W. Burrill . . L. S. NELSON 31 (Oct. '99) 468–469
B289. *Statistical Quality Control with Microcomputer Applications* by L. E. Shirland . . . . . R. W. KULP 26 (Oct. '94) 325–327
B290. *Statistical Reliability Theory* by I. B. Gertsbakh . . . . . L. LEEMIS 22 (Jan. '90) 084–085

B291. *Statistical Sampling: Past, Present and Future, Theoretical and Practical* by M. Kowalewski and J. B. Tye (eds.) . . . . . L. S. NELSON 25 (Apr. '93) 149–150
B292. *The Statistical Sleuth: A Course in Methods of Data Analysis* by F. L. Ramsey and D. W. Schafer . . . . . M. M. KILGO, III. 30 (Oct. '98) 000–000
B293. *Statistical Techniques for Data Analysis* by J. K. Taylor . . . . . L. S. NELSON 24 (Jul. '92) 168–159
B294. *Statistical Tests for Mixed Linear Models* by A. I. Khuri, T. Mathew, and B. K. Sinha . . . . . S. GILBERT AND R. CHRISTENSEN 31 (Oct. '99) 469–470
B295. *Statistics* by R. J. Barlow . . . . . L. S.NELSON 22 (Oct. '90) 333–334
B296. *Statistics and Data* by Need Morgan . . . . . T. MELANDER 28 (Jul. '96) 374–375
B297. *Statistics and Quality Control for the Workplace* by F. C. Kaminsky, R. D. Davis, and R. J. Burke . . . . . N. R. FARNUM 26 (Oct. '94) 327–328
B298. *Statistics as Principled Argument* by R. P. Abelson . . . . . L. S. NELSON 30 (Jul. '98) 306–306
B299. *Statistics for Applied Problem Solving and Decision Making* by R. Larsen, M. Marx, and B. Cooil . . . . . C. M. BORROR 30 (Jul. '98) 306–308
B300. *Statistics for Engineering Problem Solving* by S. B. Vardeman . . . . . K. A. F. COPELAND 28 (Jul. '96) 375–376
B301. *Statistics for Environmental Engineers* by P. Mac Berthouex and L. C. Brown . . . . . K. VUKOVINSKY 29 (Jul. '97) 366–367
B302. *Statistics for Research* by S. Dowdy and S. Wearden . . . . . L. S. NELSON 24 (Jul. '92) 168–168
B303. *Statistics From Scratch: An Introduction for Health Care Professionals* by D. Bowers . . . . . T. E. MELANDER 29 (Oct. '97) 491–492
B304. *Statistics in Plain English with Computer Applications* by R. S. Schulman . . . . . L. S. NELSON 25 (Oct. '93) 321–322
B305. *Statistics in Research, 4th ed.* by B. Ostle and L. C. Malone . . L. S. NELSON 21 (Jul. '89) 219–220
B306. *Statistics in Research and Development* by R. Caulcutt . . . . . R. L. MASON 25 (Jul. '93) 231–232
B307. *Statistics of Quality* by S. Ghosh, W. R. Schucany, and W. B. Smith . . . . . K. A. F. COPELAND 29 (Apr. '97) 234–235
B308. *Statistics: Principles and Methods* by R. A. Johnson and G. K. Bhattacharyya . . . . . L. DANIELS 30 (Apr. '98) 184–185
B309. *Student* by E. S. Pearson, R. L. Plackett, and G. A. Barnard . . L. S. NELSON 25 (Jan. '93) 073–074
B310. *Subset Selection in Regression* by A. J. Miller . . . . . M. KNOTT 23 (Jul. '91) 267–267
B311. *Successful Industrial Experimentation* by B. Kyle . . . . . L. S. NELSON 28 (Jul. '96) 376–378
B312. *Taguchi Methods: A Hands-On Approach* by G. Peace . . . . . R. L. MASON 26 (Jan. '94) 077–078
B313. *Taguchi Techniques for Quality Engineering* by P. J. Ross . . . . J. R. SIMPSON 28 (Oct. '96) 487–489
B314. *Testability Analysis: A Survey on Methods and Applications* by A. Hunger . . . . . M. PECHT 23 (Jan. '91) 074–075
B315. *Theory of Statistics* by M. J. Schervish . . . . . K. A. F. COPELAND 28 (Oct. '96) 489–489
B316. *Tools and Methods for the Improvement of Quality* by H. Gitlow, S. Gitlow, A. Oppenheim, and R. Oppenheim . . . . . R. L. PERRY 22 (Jan. '90) 082–083
B317. *Total Quality Control* by A. V. Feigenbaum . . . . . L. S. NELSON 24 (Jan. '92) 056–057
B318. *Total Quality Management: An IFS Executive Briefing* by R. L. Chase . . . . . W. PELZ 22 (Jul. '90) 250–251
B319. *Understanding Industrial Designed Experiments* edited by M. J. Kiemele . . . . . N. M. GIBBONS 28 (Jul. '96) 378–379
B320. *Understanding Industrial Designed Experiments* by S. R. Schmidt and R. G. Launsby . . . . . D. J. DEPRIEST 25 (Jan. '93) 069–071
B321. *Understanding Industrial Designed Experiments* by S. R. Schmidt and R. G. Launsby . . . . . B. H. GUNTER 26 (Apr. '94) 150–151
B322. *Understanding Industrial Experimentation* by D. J. Wheeler . . . L. S. NELSON 21 (Jan. '89) 073–074
B323. *Understanding Statistical Process Control* by A. Thesen and L. E. Travis . . . . . L. S. NELSON 25 (Jul. '93) 234–235
B324. *Understanding Variation, The Key to Managing Chaos* by D. J. Wheeler . . . . . L. S. NELSON 26 (Apr. '94) 152–152

B325. *Univariate Discrete Distributions* by N. L. Johnson, S. Kotz, and A. W. Kemp . . . . . P. R. NELSON 28 (Apr. '96) 263–263
B326. *Visual Explanations* by E. R. Tufte . . . . . K. A. F. COPELAND 29 (Jul. '97) 367–367
B327. *The Visual Factory: Building Participation Through Shared Information* by M. Grief . . . . . W. E. BREISCH 24 (Jan. '92) 060–061
B328. *Visualizing Data* by W. S. Cleveland . . . . . L. S. NELSON 26 (Apr. '94) 244–245
B329. *Volume 4 - How to Perform Skip-Lot and Chain Sampling, 2nd ed.* by K. S. Stephens . . . . . N. DOGANAKSOY 27 (Oct. '95) 394–395
B330. *Volume 12: How to Choose the Proper Sample Size* by G. G. Brush . . . . . G. P. MCCABE 21 (Jul. '89) 222–222
B331. *Weibull Analysis* by B. Dodson . . . . . W. J. PADGETT 27 (Oct. '95) 395–396
B332. *What Every Engineer Should Know About Quality Control* by T. Pyzdek . . . . . J. R. ENGLISH 22 (Oct. '90) 331–331
B333. *What Every Engineer Should Know About Reliability and Risk Analysis* by M. Modarres . . . . . C. J. WANG 25 (Oct. '93) 324–326
B334. *World Class Quality, Design of Experiments Made Easier, More Cost Effective Than SPC* by K. R. Bhote . . . . . L. S. NELSON 21 (Jan. '89) 076–079
B335. *World-Class Quality: Using Design of Experiments to Make it Happen* by K. R. Bhote . . . . . D. S. MOORE 25 (Apr. '93) 152–153
B336. *Zero Acceptance Number Sampling Plans* by N. I. Squeglia . . . . L. S. NELSON 28 (Jan. '96) 133–134

BOOK REVIEWERS

Atkinson, A. B98, B207
Besterfield, D. H. B231
Bisgaard, S. B101
Black-Nembhard, H. B62
Booker, J. B248
Borkowski, J. J. B80, B150, B201
Borror, C. M. B5, B11, B88, B104, B154 B160, B251, B299
Bowen, W. M. B118, B257
Brauer, D. C. B186
Breisch, W. E. B327
Brown, J. B105, B218
Champ, C. W. B20
Cheng, S. W. B136
Cohen, A. C. B209, B214, B273
Coleman, E. P. B42
Constantine, G. B141
Copeland, K. A. F. B15, B24, B25, B34, B35 B36, B37, B45, B72, B73 B74, B83, B106, B123, B127, B129 B132, B134, B135, B149, B152, B156 B215, B223, B244, B249, B255, B261 B265, B282, B300, B315, B326
Daniels, L. B308
Davis, A. B211
DePriest, D. J. B109, B184, B239, B320
DeVeaux, R. D. B256
Doganaksoy, N. B329
Dowd, J. S. B23, B235, B242, B279
Dussault, H. B. B56
Edgeman, R. L. B39, B124, B125 B133, B171, B287
Edwards, D. B97, B220
English, J. R. B195, B332
Falter, K. H. B40
Farnum, N. R. B203, B217, B260, B297
Federov, V. V. B6
Feigenbaum, I. A. B16
Foote, B. L. B187, B196
Fraser, J. M. B41
George, L. L. B153
Gibbons, N. M. B319
Gilbert, S. and Christensen, R. B294
Griffith, W. S. B114, B247
Gross, A. J. B162
Guida, M. B120
Gunst, R. F. B138
Gunter, B. B77, B321
Hare, L. B. B46, B71, B277
Heikes, R. G. B60
Heyes, G. B. B17
Hudson, P. B111
Hull, J. C. B228, B229
Irvine, J. M. B76
Jackson, J. E. B59
Johnson, P. B78
Johnston, G. B175
Kamat, S. J. B183
Kang, K. B51
Kapur, K. C. B58, B190, B193
Keats, J. B. B268
Kennedy, J. N. B85
Kilgo, III, M. M. B122, B179, B292
Knott, M. B310
Kulp, R. W. B3, B7, B241, B289
Lawson, J. B61
Leemis, L. B9, B53, B213, B290
Lewis, S. B14
Liggett, W. B142
Lim, J. -H. B199
Lovelace, C. R. B2, B147, B181, B283
Lowe, Jr., V. W. B86
Mason, R. L. B224, B306, B312
Mastrangelo, C. B121
Mazumdar, M. B21
Mazzuchi, T. A. B95
McCabe, G. P. B69, B330
McCall, C. B246, B275
Melander, T. B296, B303
Messina, W. S. B103
Miller, K. B64
Miller, O. W. B189
Moore, D. S. B102, B172, B335
Mundel, A. B. B167, B200, B202
Neath, A. A. B22
Nelson, B. L. B237
Nelson, L. S. B4, B19, B26, B49, B52, B54, B57 B65, B67, B68, B75, B82, B91, B92 B107, B128, B143, B146, B148, B163 B164, B166, B168, B169, B180, B191 B197, B204, B216, B230, B234, B253 B258, B263, B267, B269, B270, B271 B274, B278, B280, B284, B286, B288 B291, B293, B295, B298, B302, B304 B305, B309, B311, B317, B322, B323 B324, B328, B334, B336
Nelson, P. R. B31, B32, B43, B50, B79, B130 B140, B151, B155, B157, B159 B182, B188, B325
O'Brien, R. B63

Ohta, H.	B93, B117
Owen, D. B.	B90
Padgett, W. J.	B331
Park, D. H.	B84, B176
Pecht, M.	B30, B208, B227, B314
Peltz, W.	B210, B318
Perry, R. L.	B1, B116, B316
Pheatt, C. B.	B221, B222
Pollack, M.	B100
Poore, J. H.	B198
Propst, A. L.	B99
Pulat, P. S.	B205
Ramey, B. N.	B18, B178, B281
Reeves, J.	B108
Richards, J. D.	B47, B170, B245, B276
Rigdon, S. E.	B12, B177, B212
Roberts, H. V.	B110
Rowlands, H.	B48
Ruberg, S. J.	B119, B259
Ryan, T. P.	B252
Sartori, D.	B38
Schaub, D.	B185
Sebert, D. M.	B161
Shanmugam, R.	B8, B126
Shapiro, S. S.	B94
Shin, W. S.	B131, B194
Simpson, J. R.	B225, B313
Spiring, F. A.	B66, B87
Spurrier, J. D.	B10
Stadlober, E.	B173
Stanley, J. D.	B264
Stephenson, P. L.	B13, B27
Stephenson, W. R.	B55
Sullivan, G. R.	B44
Sullivan, J.	B81
Swain, J. J.	B33, B206, B236
Thibeault, A.	B70
Thompson, W. E.	B96, B238
Tobias, R. D.	B158
Tung, S. S.	B174
Ungemach, S. R.	B165
Valeroso, E. S.	B112, B139
Vance, L. C.	B243
Velleman, P.	B28
Vining, G. G.	B226, B254
Voelkel, J. G.	B233, B272
Vukovinsky, K.	B301
Wade, M. R.	B232, B266
Wang, C. J.	B333
Wasserman, G. S.	B144
Wasserman, G. S. and Mohsen, H.	B29
Williams, C.	B89, B115, B145
Wludyka, P. S.	B240
Woodall, W. H.	B192
Zahedi, H.	B219
Zimmer, L. S.	B250, B262
Zimmer, W.	B113

CORRIGENDA

	Vo.	(Mo. Yr.)	Pages
BAIN, L. J. AND ENGELHARDT, M., *Approximate Distributional Results Based on the Maximum Likelihood Estimators for the Weibull Distribution*	18	(Jul. '86)	174–181
(correction)	23	(Oct. '91)	382–382
BISGAARD, S. AND FULLER, H. T., *Sample Size Estimates for 2^{k-p} Designs With Binary Responses*	27	(Oct. '95)	344–354
(correction)	28	(Oct. '96)	496–496
BOYLES, R. A., *The Taguchi Capability Index*	23	(Jan. '91)	017–026
(correction)	23	(Oct. '91)	382–383
CHAKRABORTI, S. AND GIBBONS, J. D., *One-Sided Nonparametric Comparison of Treatments with a Standard in the One-Way Layout*	23	(Apr. '91)	102–106
(correction)	23	(Oct. '91)	383–383
CHANG, T. C. AND GAN, F. F., *A Cumulative Sum Control Chart for Monitoring Process Variance*	27	(Apr. '95)	109–119
(correction)	27	(Oct. '95)	402–402
CHOU, Y. M., OWEN, D. B. AND BORREGO, A. S. A., *Lower Confidence Limits On Process Capability Indices*	22	(Jul. '90)	223–229
(correction)	24	(Oct. '92)	251–251
CORNELL, J. A. AND MONTGOMERY, D. C., *Interaction Models as Alternatives to Low-Order Polynomials*	28	(Apr. '96)	163–176
(correction)	29	(Oct. '97)	501–501
CROWDER, S. V., HAWKINS, D. M., REYNOLDS JR., M. R. AND YASHIN, E., *Discussion on Statistically-Based Process Monitoring and Control*	29	(Jan. '97)	120–161
(correction)	30	(Oct. '98)	423–423
CRYER, J. D. AND RYAN, T. P., *The Estimation of Sigma for an X Chart: $\overline{MR}/d_2$ or S/c_4?*	22	(Jul. '90)	187–192
(correction)	23	(Oct. '91)	383–383
DHAVALE, D. G., *Computational Approaches to Estimating Negative Binomial Parameters from Count Data*	21	(Jan. '89)	051–064
(correction)	22	(Oct. '90)	341–341
EDWARDS, D., *Review of Resampling-Based Multiple Testing by P. H. Westfall and S. S. Young*	27	(Jul. '95)	272–273
(correction)	27	(Oct. '95)	403–403
KASPERSKI, W. J., SCHNEIDER, H. AND JOHNSON, K. L., *Analyzing Unreplicated Factorials Using the n Smallest Contrasts*	27	(Oct. '95)	377–386
(correction)	28	(Oct. '96)	496–496

KRISHNAMOORTHY, K AND SHAH, A. K., *Testing Equality of Several Normal Means to a Specified Standard*
27 (Apr. '95) 132–138
(correction) 27 (Oct. '95) 402–402

KUSHLER, R. H. AND HURLEY, P., *Confidence Bounds for Capability Indices*
24 (Oct. '92) 188–195
(correction) 25 (Oct. '93) 333–333

LIN, D. K. J. AND TU, W., *Dual Response Surface Optimization*
27 (Jan. '95) 034–039
(correction) 28 (Oct. '96) 496–496

MASON, R. L., TRACY, N. D. AND YOUNG, J. C., *Decomposition of T^2 For Multivariate Control Chart Interpretation*
27 (Apr. '95) 099–108
(correction) 30 (Oct. '98) 423–423

MYERS, R. H. AND MONTGOMERY, D. C., *A Tutorial on Generalized Liner Models*
29 (Jul. '97) 274–291
(correction) 30 (Oct. '98) 423–424

NELSON, L. S., *The Anderson-Darling Test for Normality*
30 (Jul. '98) 298–299
(correction) 31 (Oct. '99) 479–479

NELSON, L. S., *Answers to a True-False Test in Quality Control and Statistics*
28 (Oct. '96) 480–482
(correction) 30 (Oct. '98) 423–423

NELSON, L. S., *Critical Values for a Cluster Analysis Approach to Multiple Comparisons*
22 (Jan. '90) 074–077
(correction) 22 (Oct. '90) 342–342
(correction) 23 (Oct. '91) 382–382

NELSON, L. S., *Evaluating Overlapping Confidence Intervals*
21 (Apr. '89) 140–141
(correction) 21 (Oct. '89) 306–306

NELSON, L. S., *Notes on the Use of Randomization in Experimentation*
26 (Apr. '94) 123–126
(correction) 28 (Oct. '96) 496–496

NELSON, L. S., *A Randomization Test for Ordered Alternatives*
23 (Jul. '91) 213–224
(correction) 24 (Oct. '92) 251–251

NELSON, L. S., *Review of Statistically Speaking, A Dictionary of Quotations*
29 (Apr. '97) 232–233
(correction) 29 (Oct. '97) 501–501

NELSON, L. S., *Review of Student by E. S. Pearson, R. L. Plackett and G. A. Barnard*
25 (Jan. '93) 073–074
(correction) 25 (Oct. '93) 333–333

NELSON, L. S., *Review of Visualizing Data by W. S. Cleveland*
26 (Jul. '94) 244–245
(correction) 26 (Oct. '94) 334–334

NELSON, L. S., *A Stabilized Normal Probability Plotting Technique*
21 (Jul. '89) 213–215
(correction) 22 (Oct. '90) 341–341

NELSON, L. S., *Tests on Early Failures—The Precedence Life Test* 25 (Apr. '93) 140–143
(correction) 27 (Oct. '95) 402–402

NELSON, L. S., *Use of the Range to Estimate Variability* 07 (Jan. '75) 046–048
(correction) 29 (Oct. '97) 501–501

NELSON, L. S., *Using Nested Designs: II. Confidence Limits for Standard Deviations* 27 (Jul. '95) 265–265
(correction) 27 (Oct. '95) 403–403

NELSON, P. R., *Multiple Comparisons of Means Using Simultaneous Confidence Intervals* 21 (Oct. '89) 232–241
(correction) 22 (Oct. '90) 341–342

NELSON, W., *Graphical Analysis of System Repair Data* 20 (Jan. '88) 024–035
(correction) 21 (Oct. '89) 306–306

PEARN, W. L. , KOTZ, S. AND JOHNSON, N. L., *Distributional and Inferential Properties of Process Capability Indices* 24 (Oct. '92) 216–231
(correction) 25 (Oct. '93) 333–333

QUESENBERRY, C. P., *Geometric Q Charts for High Quality Processes* 27 (Oct. '95) 304–315
(correction) 28 (Oct. '96) 496–496

QUESENBERRY, C. P., *On Properties of Q Charts for Variables* 27 (Jul. '95) 184–203
(correction) 27 (Oct. '95) 402–402

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